MUX50x 36-V, Low-Capacitance, Low-Leakage-Current, Precision Analog Multiplexers

1 Features

- Low On-Capacitance
  - MUX506: 13.5 pF
  - MUX507: 8.7 pF
- Low Input Leakage: 1 pA
- Low Charge Injection: 0.31 pC
- Rail-to-Rail Operation
- Wide Supply Range: ±5 V to ±18 V, 10 V to 36 V
- Low On-Resistance: 125 Ω
- Transition Time: 97 ns
- Break-Before-Make Switching Action
- EN Pin Connectable to V_{DD}
- Logic Levels: 2 V to V_{DD}
- Low Supply Current: 45 µA
- ESD Protection HBM: 2000 V
- Industry-Standard TSSOP/ SOIC Package

2 Applications

- Factory Automation and Industrial Process Control
- Programmable Logic Controllers (PLC)
- Analog Input Modules
- ATE Test Equipment
- Digital Multimeters
- Battery Monitoring Systems

3 Description

The MUX506 and MUX507 (MUX50x) are modern complementary metal-oxide semiconductor (CMOS) precision analog multiplexers (muxes). The MUX506 offers 16:1 single-ended channels, whereas the MUX507 offers differential 8:1 or dual 8:1 single-ended channels. The MUX506 and MUX507 work equally well with either dual supplies (±5 V to ±18 V) or a single supply (10 V to 36 V). These devices also perform well with symmetric supplies (such as V_{DD} = 12 V, V_{SS} = –12 V), and unsymmetric supplies (such as V_{DD} = 12 V, V_{SS} = –5 V). All digital inputs have transistor-transistor logic (TTL) compatible thresholds, providing both TTL and CMOS logic compatibility when operating in the valid supply voltage range.

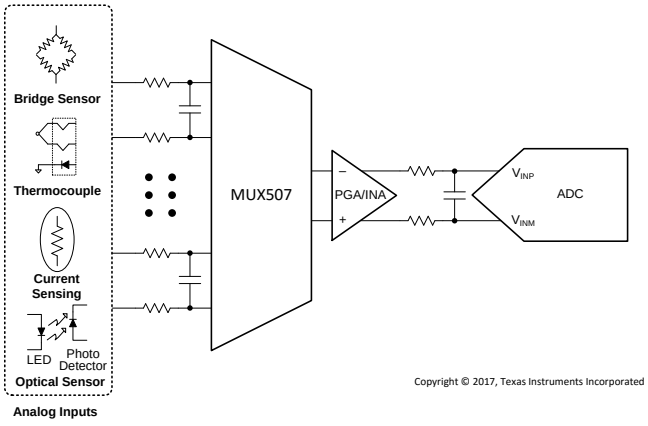
The MUX507 and MUX507 have very low on- and off-leakage currents, allowing these multiplexers to switch signals from high input impedance sources with minimal error. A low supply current of 45 µA enables use in power-sensitive applications.

Device Information(1)

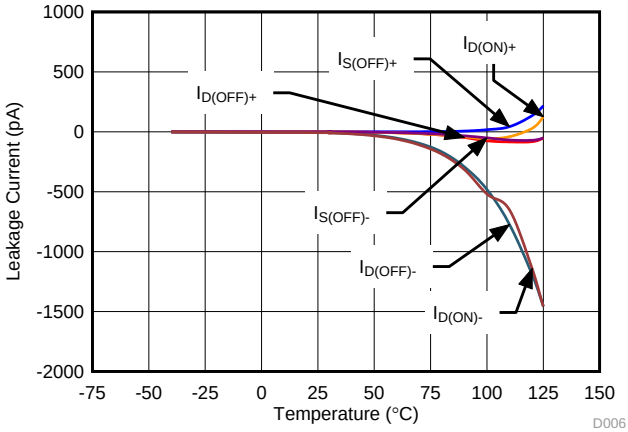
PART NUMBER	PACKAGE	BODY SIZE (NOM)
MUX506 MUX507	TSSOP (28)	9.70 mm × 6.40 mm
	SOIC (28)	17.9 mm × 7.50 mm

(1) For all available packages, see the package option addendum at the end of the data sheet.

Simplified Schematic



Leakage Current vs Temperature



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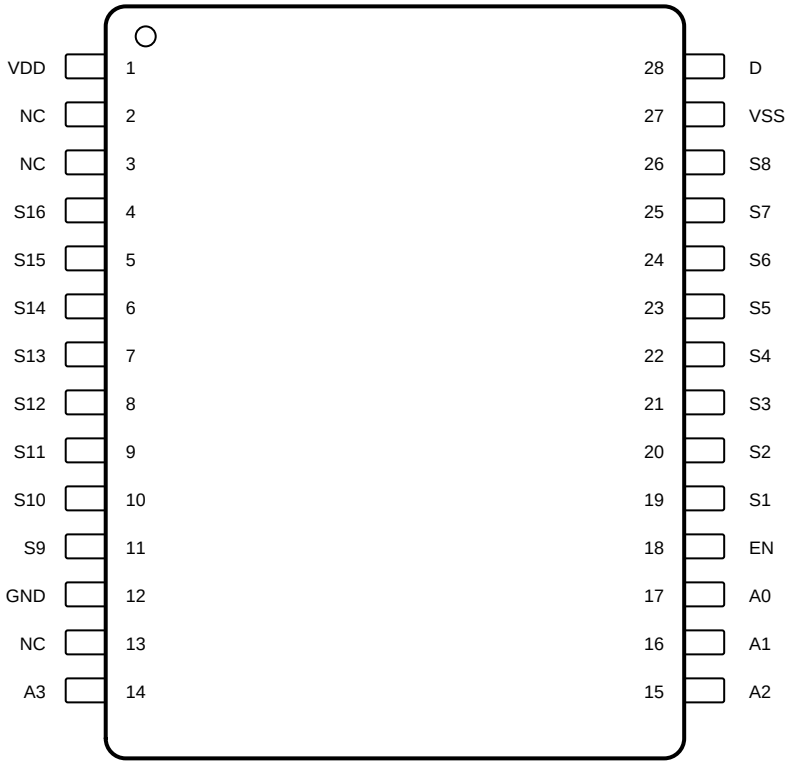
4 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

Changes from Original (November 2016) to Revision A	Page
• Changed Transition Time From: 85 ns To: 97ns (Typ) in the *Features* list	1
• Added SOIC packages to *Feature* and *Device Information*	1
• Added the DW (SOIC) package to the *Pin Configuration and Functions* section	3
• Added SOIC package to the *Thermal Information* table	7
• Changed Transition time Typ value From 85: ns To: 97ns for ±15 V supplies in the *Electrical Characteristics: Dual Supply* table	8
• Added additional specifications for the SOIC packages (Q_J, Off-isolation, and channel-to-channel crosstalk) for ±15 V supplies in *Electrical Characteristics: Dual Supply*	8
• Changed Transition time Typ value From: 91 To: 102 ns for 12 V supply in the *Electrical Characteristics: Single Supply* table	10
• Added additional specifications for the SOIC packages (Q_J, Off-isolation, and channel-to-channel crosstalk) for 12 V supply in *Electrical Characteristics: Single Supply*	10
• Added NOTE to the *Application and Implementation* section	28

5 Pin Configuration and Functions

MUX506: PW and DW Packages
28-Pin TSSOP and SOIC
Top View



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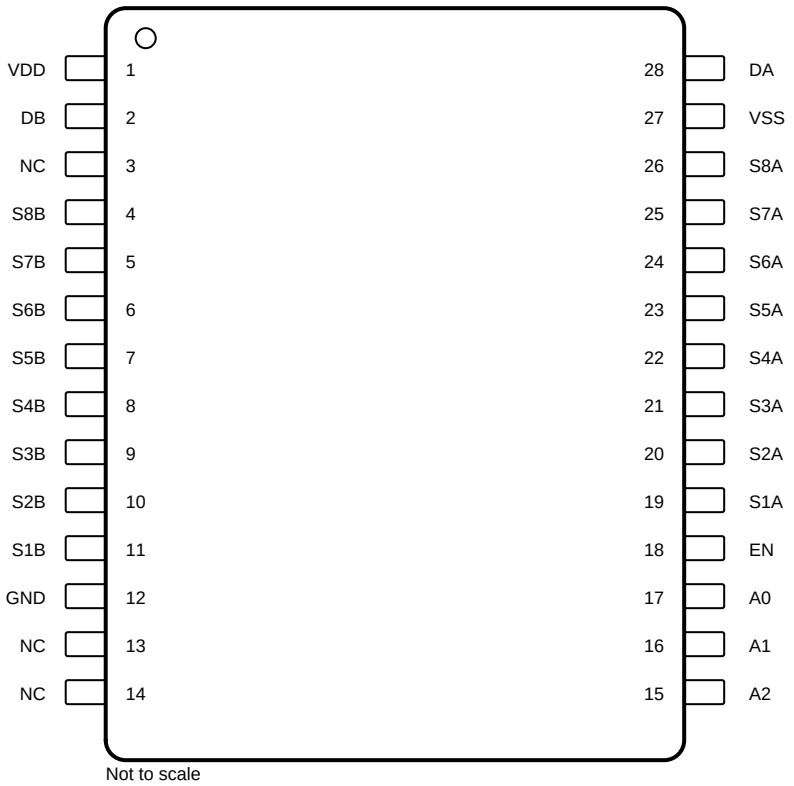
Pin Functions: MUX506

PIN		FUNCTION	DESCRIPTION
NAME	NO.		
A0	17	Digital input	Address line 0
A1	16	Digital input	Address line 1
A2	15	Digital input	Address line 2
A3	14	Digital input	Address line 3
D	28	Analog input or output	Drain pin. Can be an input or output.
EN	18	Digital input	Active high digital input. When this pin is low, all switches are turned off. When this pin is high, the A[3:0] logic inputs determine which switch is turned on.
GND	12	Power supply	Ground (0 V) reference
NC	2, 3, 13	No connect	Do not connect
S1	19	Analog input or output	Source pin 1. Can be an input or output.
S2	20	Analog input or output	Source pin 2. Can be an input or output.
S3	21	Analog input or output	Source pin 3. Can be an input or output.
S4	22	Analog input or output	Source pin 4. Can be an input or output.
S5	23	Analog input or output	Source pin 5. Can be an input or output.
S6	24	Analog input or output	Source pin 6. Can be an input or output.
S7	25	Analog input or output	Source pin 7. Can be an input or output.
S8	26	Analog input or output	Source pin 8. Can be an input or output.
S9	11	Analog input or output	Source pin 9. Can be an input or output.

Pin Functions: MUX506 (continued)

PIN		FUNCTION	DESCRIPTION
NAME	NO.		
S10	10	Analog input or output	Source pin 10. Can be an input or output.
S11	9	Analog input or output	Source pin 11. Can be an input or output.
S12	8	Analog input or output	Source pin 12. Can be an input or output.
S13	7	Analog input or output	Source pin 13. Can be an input or output.
S14	6	Analog input or output	Source pin 14. Can be an input or output.
S15	5	Analog input or output	Source pin 15. Can be an input or output.
S16	4	Analog input or output	Source pin 16. Can be an input or output.
VDD	1	Power supply	Positive power supply. This pin is the most positive power-supply potential. For reliable operation, connect a decoupling capacitor ranging from 0.1 µF to 10 µF between VDD and GND.
VSS	27	Power supply	Negative power supply. This pin is the most negative power-supply potential. In single-supply applications, this pin can be connected to ground. For reliable operation, connect a decoupling capacitor ranging from 0.1 µF to 10 µF between VSS and GND.

MUX507: PW and DW Package
28-Pin TSSOP and SOIC
Top View



Not to scale

Pin Functions: MUX507

PIN		FUNCTION	DESCRIPTION
NAME	NO.		
A0	17	Digital input	Address line 0
A1	16	Digital input	Address line 1
A2	15	Digital input	Address line 2
DA	28	Analog input or output	Drain pin A. Can be an input or output.

Pin Functions: MUX507 (continued)

PIN		FUNCTION	DESCRIPTION
NAME	NO.		
DB	2	Analog input or output	Drain pin B. Can be an input or output.
EN	18	Digital input	Active high digital input. When this pin is low, all switches are turned off. When this pin is high, the A[2:0] logic inputs determine which pair of switches is turned on.
GND	12	Power supply	Ground (0 V) reference
NC	3, 13, 14	No connect	Do not connect
S1A	19	Analog input or output	Source pin 1A. Can be an input or output.
S2A	20	Analog input or output	Source pin 2A. Can be an input or output.
S3A	21	Analog input or output	Source pin 3A. Can be an input or output.
S4A	22	Analog input or output	Source pin 4A. Can be an input or output.
S5A	23	Analog input or output	Source pin 5A. Can be an input or output.
S6A	24	Analog input or output	Source pin 6A. Can be an input or output.
S7A	25	Analog input or output	Source pin 7A. Can be an input or output.
S8A	26	Analog input or output	Source pin 8A. Can be an input or output.
S1B	11	Analog input or output	Source pin 1B. Can be an input or output.
S2B	10	Analog input or output	Source pin 2B. Can be an input or output.
S3B	9	Analog input or output	Source pin 3B. Can be an input or output.
S4B	8	Analog input or output	Source pin 4B. Can be an input or output.
S5B	7	Analog input or output	Source pin 5B. Can be an input or output.
S6B	6	Analog input or output	Source pin 6B. Can be an input or output.
S7B	5	Analog input or output	Source pin 7B. Can be an input or output.
S8B	4	Analog input or output	Source pin 8B. Can be an input or output.
VDD	1	Power supply	Positive power supply. This pin is the most positive power supply potential. For reliable operation, connect a decoupling capacitor ranging from 0.1 µF to 10 µF between VDD and GND.
VSS	27	Power supply	Negative power supply. This pin is the most negative power supply potential. In single-supply applications, this pin can be connected to ground. For reliable operation, connect a decoupling capacitor ranging from 0.1 µF to 10 µF between VSS and GND.

6 Specifications

6.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)(1)

			MIN	MAX	UNIT
Voltage	Supply	V_{DD}	–0.3	40	V
		V_{SS}	–40	0.3	
		$V_{DD} – V_{SS}$		40	
	Digital pins(2): EN, A0, A1, A2, A3		$V_{SS} – 0.3$	$V_{DD} + 0.3$	
	Analog pins(2): Sx, SxA, SxB, D, DA, DB		$V_{SS} – 2$	$V_{DD} + 2$	
Current(3)			–30	30	mA
Temperature	Operating, T_A		–55	150	°C
	Junction, T_J			150	
	Storage, T_{stg}		–65	150	

(1) Stresses beyond those listed under *Absolute Maximum Ratings* may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under *Recommended Operating Conditions*. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
(2) Voltage limits are valid if current is limited to ±30 mA.
(3) Only one pin at a time.

6.2 ESD Ratings

			VALUE	UNIT
$V_{(ESD)}$	Electrostatic discharge	Human-body model (HBM), per ANSI/ESDA/JEDEC JS-001(1)	2000	V
		Charged-device model (CDM), per JEDEC specification JESD22-C101(2)	500	

(1) JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.
(2) JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.

6.3 Recommended Operating Conditions

			MIN	NOM	MAX	UNIT
V_{DD}(1)	Positive power-supply voltage	Dual supply	5		18	V
		Single supply	10		36	
V_{SS}(2)	Negative power-supply voltage (dual supply)		–5		–18	V
$V_{DD} – V_{SS}$	Supply voltage		10		36	V
V_S	Source pins voltage(3)		V_{SS}		V_{DD}	V
V_D	Drain pins voltage		V_{SS}		V_{DD}	V
V_{EN}	Enable pin voltage		V_{SS}		V_{DD}	V
V_A	Address pins voltage		V_{SS}		V_{DD}	V
I_{CH}	Channel current (T_A = 25°C)		–25		25	mA
T_A	Operating temperature		–40		125	°C

(1) When V_{SS} = 0 V, V_{DD} can range from 10 V to 36 V.
(2) V_{DD} and V_{SS} can be any value as long as 10 V ≤ ($V_{DD} – V_{SS}$) ≤ 36 V.
(3) V_S is the voltage on all the S pins.

6.4 Thermal Information

THERMAL METRIC[1]		MUX50x		UNIT
		PW (TSSOP)	DW (SOIC)	
		28 PINS	28 PINS	
$R_{\theta JA}$	Junction-to-ambient thermal resistance	79.8	53.6	°C/W
$R_{\theta JC(top)}$	Junction-to-case (top) thermal resistance	24.0	30.1	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	37.6	28.5	°C/W
ψ_{JT}	Junction-to-top characterization parameter	1.2	9.0	°C/W
ψ_{JB}	Junction-to-board characterization parameter	37.1	28.4	°C/W
$R_{\theta JC(bot)}$	Junction-to-case (bottom) thermal resistance	N/A	N/A	°C/W

(1) For more information about traditional and new thermal metrics, see the *Semiconductor and IC Package Thermal Metrics* application report.

6.5 Electrical Characteristics: Dual Supply

at T_A = 25°C, V_{DD} = 15 V, and V_{SS} = –15 V (unless otherwise noted)

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
ANALOG SWITCH							
	Analog signal range	T_A = –40°C to +125°C		V_{SS}		V_{DD}	V
R_{ON}	On-resistance	V_S = 0 V, I_S = –1 mA			125	170	Ω
		V_S = ±10 V, I_S = –1 mA			145	200	
			T_A = –40°C to +85°C			230	
			T_A = –40°C to +125°C			250	
ΔR_{ON}	On-resistance mismatch between channels	V_S = ±10 V, I_S = –1 mA			6	9	Ω
			T_A = –40°C to +85°C			14	
			T_A = –40°C to +125°C			16	
R_{FLAT}	On-resistance flatness	V_S = 10 V, 0 V, –10 V			20	45	Ω
			T_A = –40°C to +85°C			53	
			T_A = –40°C to +125°C			58	
	On-resistance drift	V_S = 0 V			0.62		Ω/°C
$I_{S(OFF)}$	Input leakage current	Switch state is off, V_S = ±10 V, V_D = ±10 V[1]		–1	–0.001	1	nA
			T_A = –40°C to +85°C	–10		10	
			T_A = –40°C to +125°C	–25		25	
$I_{D(OFF)}$	Output off-leakage current	Switch state is off, V_S = ±10 V, V_D = ±10 V[1]		–1	–0.01	1	nA
			T_A = -40°C to +85°C	–10		10	
			T_A = -40°C to +125°C	–25		25	
$I_{D(ON)}$	Output on-leakage current	Switch state is on, V_D = ±10 V, V_S = floating		–1	–0.01	1	nA
			T_A = –40°C to +85°C	–10		10	
			T_A = –40°C to +125°C	–50		50	
LOGIC INPUT							
V_{IH}	Logic voltage high			2			V
V_{IL}	Logic voltage low					0.8	V
I_D	Input current					0.1	µA

(1) When V_S is positive, V_D is negative, and vice versa.

Electrical Characteristics: Dual Supply (continued)

at T_A = 25°C, V_{DD} = 15 V, and V_{SS} = –15 V (unless otherwise noted)

PARAMETER		TEST CONDITIONS			MIN	TYP	MAX	UNIT
SWITCH DYNAMICS(2)								
t_{ON}	Enable turn-on time	V_S = ±10 V, R_L = 300 Ω, C_L= 35 pF				82	136	ns
			T_A = –40°C to +85°C				145	
			T_A = –40°C to +125°C				151	
t_{OFF}	Enable turn-off time	V_S = ±10 V, R_L = 300 Ω, C_L= 35 pF				63	78	ns
			T_A = –40°C to +85°C				89	
			T_A = –40°C to +125°C				97	
t_t	Transition time	V_S = 10 V, R_L = 300 Ω, C_L= 35 pF,				97	143	ns
			T_A = –40°C to +85°C				151	
			T_A = –40°C to +125°C				157	
t_{BBM}	Break-before-make time delay	V_S = 10 V, R_L = 300 Ω, C_L= 35 pF, T_A = –40°C to +125°C			30	54		ns
Q_J	Charge injection	C_L = 1 nF, R_S = 0 Ω	V_S = 0 V	TSSOP package		0.31		pC
				SOIC package		0.67		
			V_S = –15 V to +15 V	TSSOP package		±0.9		
				SOIC package		±1.1		
	Off-isolation	R_L = 50 Ω, V_S = 1 V_{RMS}, f = 1 MHz	Nonadjacent channel to D, DA, DB	TSSOP package		–98		dB
				SOIC package		–94		
			Adjacent channel to D, DA, DB	TSSOP package		–94		
				SOIC package		–88		
	Channel-to-channel crosstalk	R_L = 50 Ω, V_S = 1 V_{RMS}, f = 1 MHz	Nonadjacent channels	TSSOP package		–100		dB
				SOIC package		–96		
			Adjacent channels	TSSOP package		–88		
				SOIC package		–83		
$C_{S(OFF)}$	Input off-capacitance	f = 1 MHz, V_S = 0 V				2.1	3	pF
$C_{D(OFF)}$	Output off-capacitance	f = 1 MHz, V_S = 0 V	MUX506			11.1	12.2	pF
			MUX507			6.4	7.5	
$C_{S(ON)}$, $C_{D(ON)}$	Output on-capacitance	f = 1 MHz, V_S = 0 V	MUX506			13.5	15	pF
			MUX507			8.7	10.2	
POWER SUPPLY								
	V_{DD} supply current	All V_A = 0 V or 3.3 V, V_S = 0 V, V_{EN} = 3.3 V,				45	59	µA
			T_A = –40°C to +85°C				62	
			T_A = –40°C to +125°C				85	
	V_{SS} supply current	All V_A = 0 V or 3.3 V, V_S = 0 V, V_{EN} = 3.3 V,				26	34	µA
			T_A = –40°C to +85°C				37	
			T_A = –40°C to +125°C				58	

(2) Specified by design; not subject to production testing.

6.6 Electrical Characteristics: Single Supply

at T_A = 25°C, V_{DD} = 12 V, and V_{SS} = 0 V (unless otherwise noted)

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
ANALOG SWITCH							
	Analog signal range	T_A = –40°C to +125°C		V_{SS}		V_{DD}	V
R_{ON}	On-resistance	V_S = 10 V, I_S = –1 mA			235	340	Ω
			T_A = –40°C to +85°C			390	
			T_A = –40°C to +125°C			430	
ΔR_{ON}	On-resistance match	V_S = 10 V, I_S = –1 mA			7	20	Ω
			T_A = –40°C to +85°C			35	
			T_A = –40°C to +125°C			40	
	On-resistance drift	V_S = 10 V			1.07		Ω/°C
$I_{S(OFF)}$	Input leakage current	Switch state is off, V_S = 1 V and V_D = 10 V, or V_S = 10 V and V_D = 1 V(1)		–1	0.001	1	nA
			T_A = –40°C to +85°C	–10		10	
			T_A = –40°C to +125°C	–25		25	
$I_{D(OFF)}$	Output off leakage current	Switch state is off, V_S = 1 V and V_D = 10 V, or V_S = 10 V and V_D = 1 V(1)		–1	0.01	1	nA
			T_A = –40°C to +85°C	–10		10	
			T_A = –40°C to +125°C	–25		25	
$I_{D(ON)}$	Output on leakage current	Switch state is on, V_D = 1 V and 10 V, V_S = floating		–1	0.02	1	nA
			T_A = –40°C to +85°C	–10		10	
			T_A = –40°C to +125°C	–50		50	
LOGIC INPUT							
V_{IH}	Logic voltage high			2.0			V
V_{IL}	Logic voltage low					0.8	V
I_D	Input current					0.1	µA

(1) When V_S is 1 V, V_D is 10 V, and vice versa.

Electrical Characteristics: Single Supply (continued)

at T_A = 25°C, V_{DD} = 12 V, and V_{SS} = 0 V (unless otherwise noted)

PARAMETER		TEST CONDITIONS			MIN	TYP	MAX	UNIT
SWITCH DYNAMIC CHARACTERISTICS(2)								
t_{ON}	Enable turn-on time	V_S = 8 V, R_L = 300 Ω, C_L= 35 pF				90	145	ns
			T_A = –40°C to +85°C				145	
			T_A = –40°C to +125°C				149	
t_{OFF}	Enable turn-off time	V_S = 8 V, R_L = 300 Ω, C_L= 35 pF				66	84	ns
			T_A = –40°C to +85°C				94	
			T_A = –40°C to +125°C				102	
t_t	Transition time	V_S = 8 V, C_L= 35 pF				107	147	ns
		V_S = 8 V, R_L = 300 Ω, C_L= 35 pF,	T_A = –40°C to +85°C				153	
		V_S = 8 V, R_L = 300 Ω, C_L= 35 pF,	T_A = –40°C to +125°C				155	
t_{BBM}	Break-before-make time delay	V_S = 8 V, R_L = 300 Ω, C_L= 35 pF, T_A = –40°C to +125°C			30	54		ns
Q_J	Charge injection	C_L = 1 nF, R_S = 0 Ω	V_S = 6 V	TSSOP package		0.12		pC
				SOIC package		0.38		
			V_S = 0 V to 12 V	TSSOP		±0.17		
				SOIC package		±0.48		
	Off-isolation	R_L = 50 Ω, V_S = 1 V_{RMS}, f = 1 MHz	Nonadjacent channel to D, DA, DB	TSSOP package		–97		dB
				SOIC package		–94		
			Adjacent channel to D, DA, DB	TSSOP package		–94		
				SOIC package		–88		
	Channel-to-channel crosstalk	R_L = 50 Ω, V_S = 1 V_{RMS}, f = 1 MHz	Nonadjacent channels	TSSOP package		–100		dB
				SOIC package		–99		
			Adjacent channels	TSSOP		-88		
				SOIC package		-83		
$C_{S(OFF)}$	Input off-capacitance	f = 1 MHz, V_S = 6 V				2.4	3.4	pF
$C_{D(OFF)}$	Output off-capacitance	f = 1 MHz, V_S = 6 V	MUX506			14	15.4	pF
			MUX507			7.8	9.1	
$C_{S(ON)}$, $C_{D(ON)}$	Output on-capacitance	f = 1 MHz, V_S = 6 V	MUX506			16.2	18	pF
			MUX507			9.9	11.6	
POWER SUPPLY								
	V_{DD} supply current	All V_A = 0 V or 3.3 V, V_S= 0 V, V_{EN} = 3.3 V				41	59	µA
			T_A = –40°C to +85°C				62	
			T_A = –40°C to +125°C				83	
	V_{SS} supply current	All V_A = 0 V or 3.3 V, V_S = 0 V, V_{EN} = 3.3 V				22	34	µA
			T_A = –40°C to +85°C				37	
			T_A = –40°C to +125°C				57	

(2) Specified by design, not subject to production test.

6.7 Typical Characteristics

at T_A = 25°C, V_{DD} = 15 V, and V_{SS} = –15 V (unless otherwise noted)

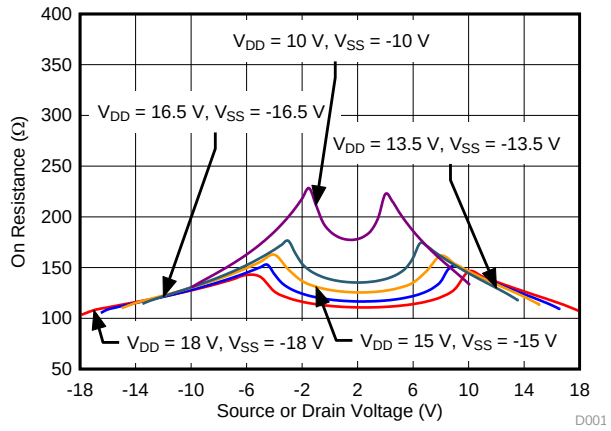
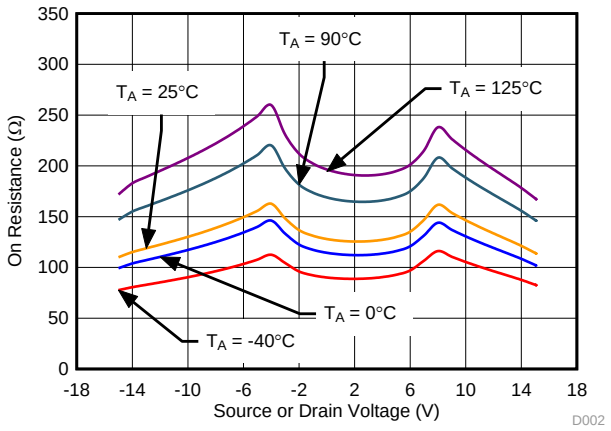


Figure 1. On-Resistance vs Source or Drain Voltage



V_{DD} = 15 V, V_{SS} = –15 V

Figure 2. On-Resistance vs Source or Drain Voltage

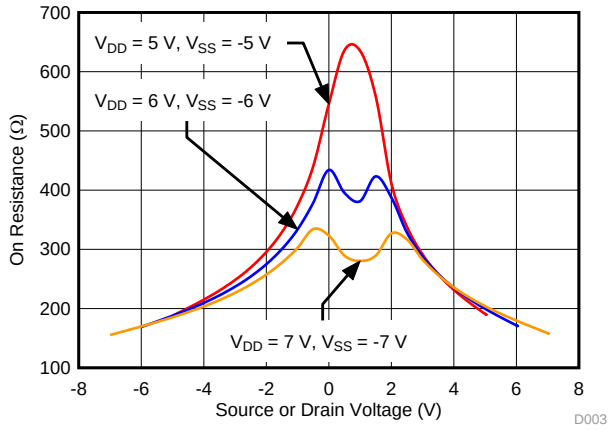
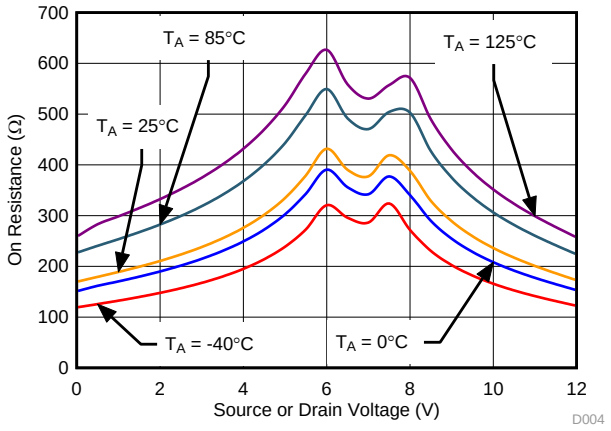


Figure 3. On-Resistance vs Source or Drain Voltage



V_{DD} = 12 V, V_{SS} = 0 V

Figure 4. On-Resistance vs Source or Drain Voltage

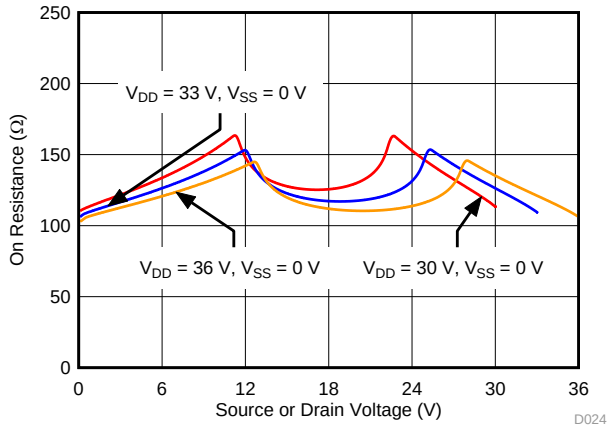


Figure 5. On-Resistance vs Source or Drain Voltage

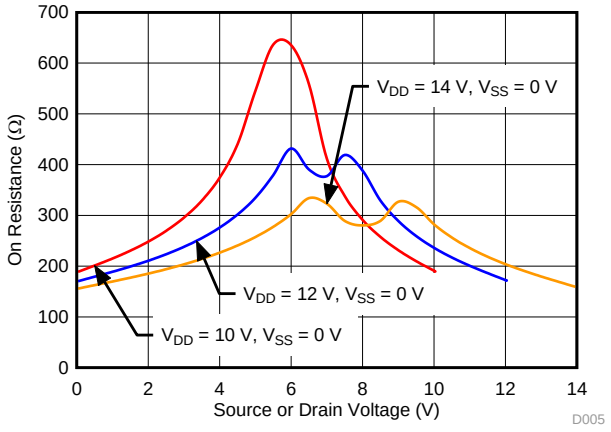
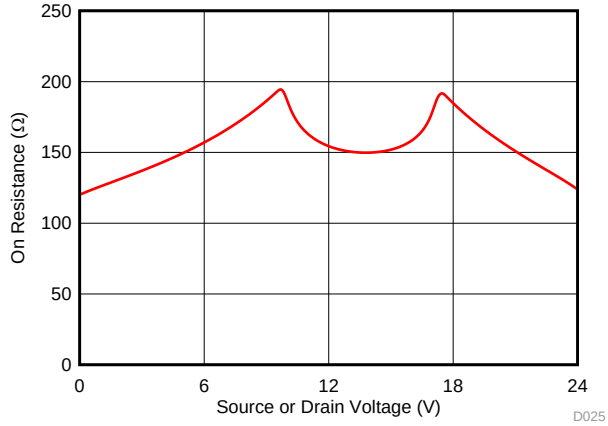


Figure 6. On-Resistance vs Source or Drain Voltage

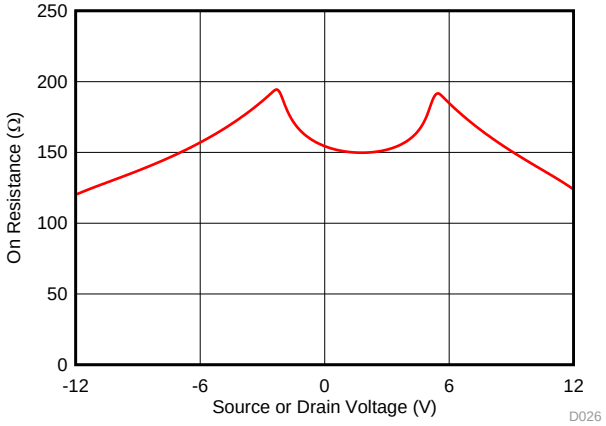
Typical Characteristics (continued)

at T_A = 25°C, V_{DD} = 15 V, and V_{SS} = –15 V (unless otherwise noted)



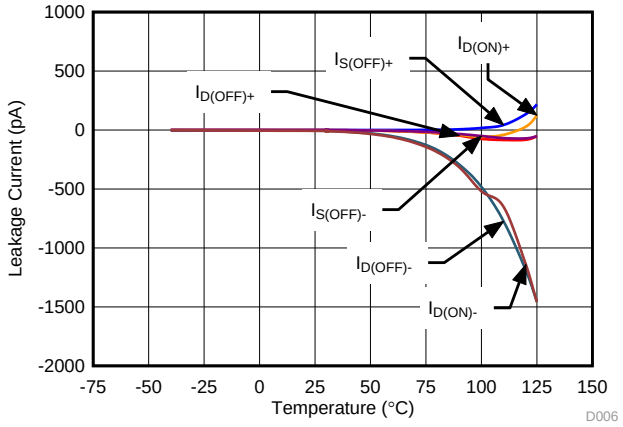
V_{DD} = 24 V, V_{SS} = 0 V

Figure 7. On-Resistance vs Source or Drain Voltage



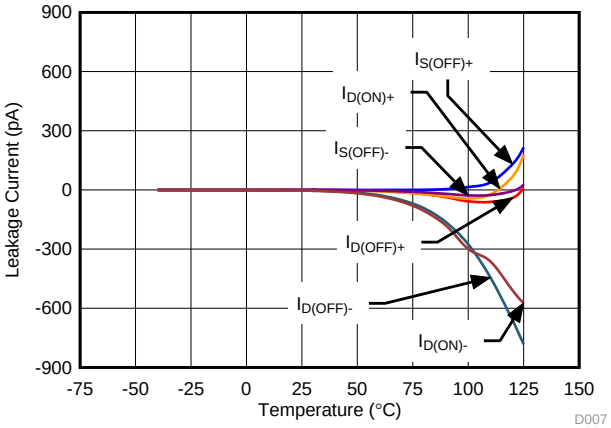
V_{DD} = 12 V, V_{SS} = –12 V

Figure 8. On-Resistance vs Source or Drain Voltage



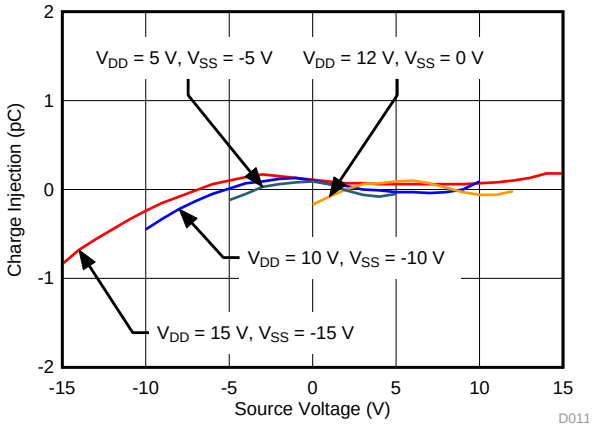
V_{DD} = 15 V, V_{SS} = –15 V

Figure 9. Leakage Current vs Temperature



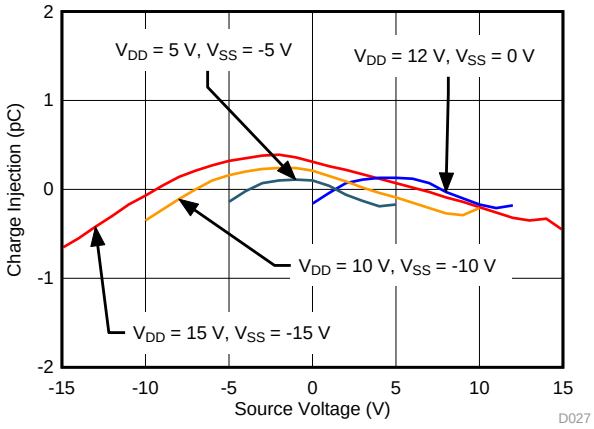
V_{DD} = 12 V, V_{SS} = 0 V

Figure 10. Leakage Current vs Temperature



MUX506, source-to-drain

Figure 11. Charge Injection vs Source Voltage

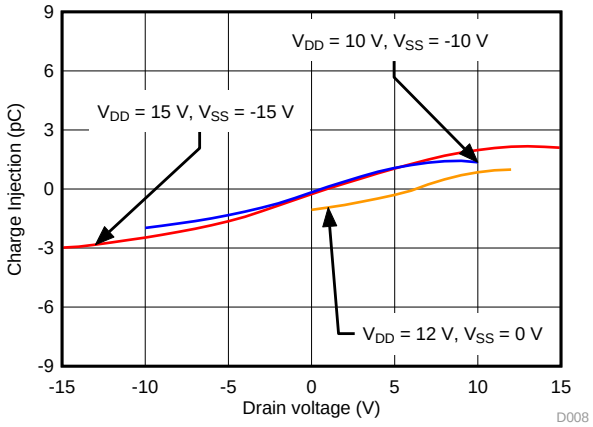


MUX507, source-to-drain

Figure 12. Charge Injection vs Source Voltage

Typical Characteristics (continued)

at T_A = 25°C, V_{DD} = 15 V, and V_{SS} = –15 V (unless otherwise noted)



Drain-to-source

Figure 13. Charge Injection vs Drain Voltage

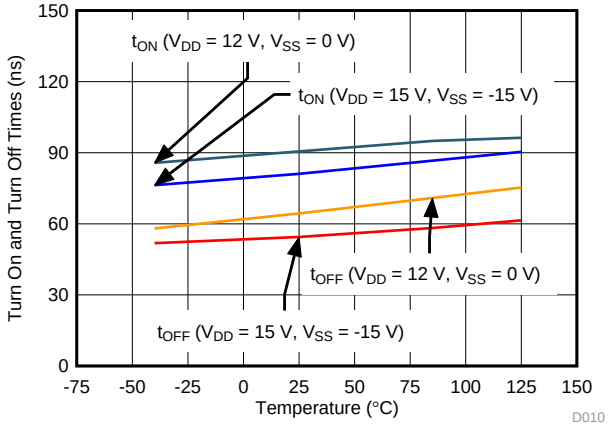


Figure 14. Turn-On and Turn-Off Times vs Temperature

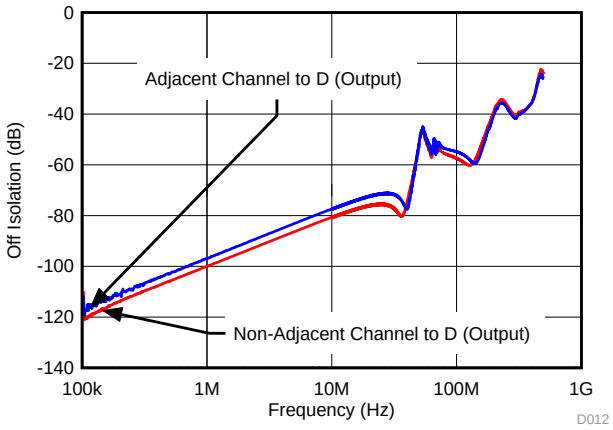


Figure 15. Off Isolation vs Frequency

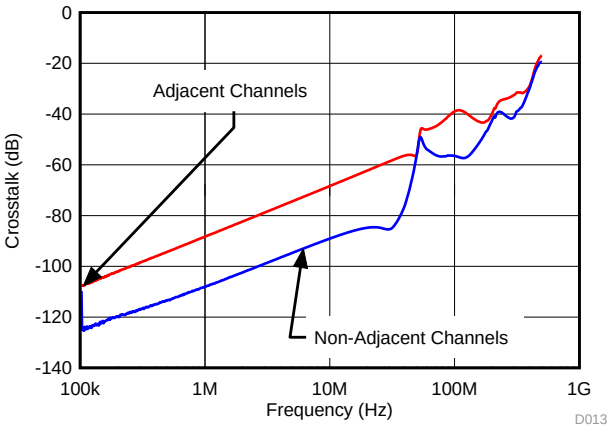


Figure 16. Crosstalk vs Frequency

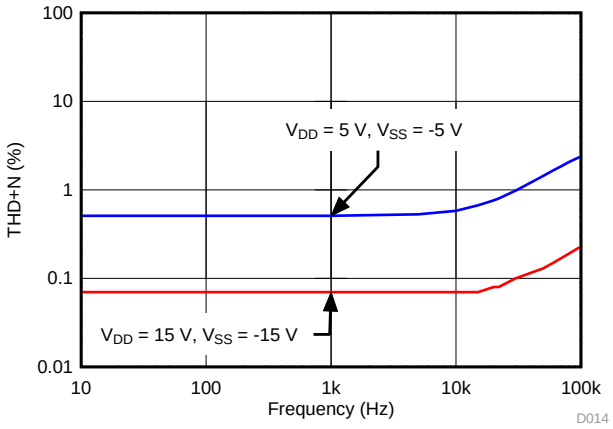


Figure 17. THD+N vs Frequency

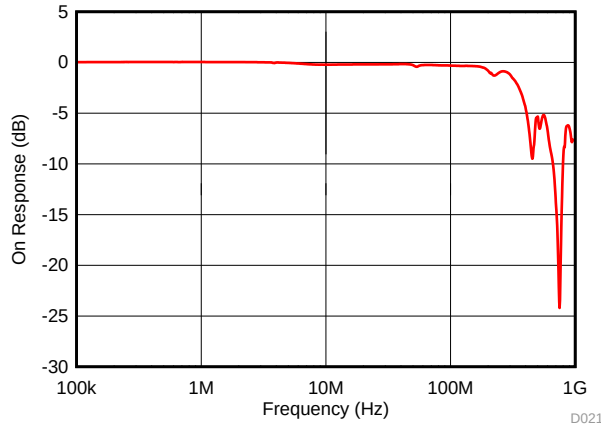
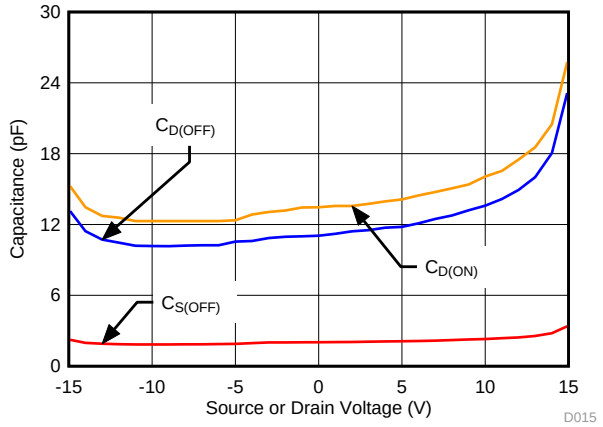


Figure 18. On Response vs Frequency

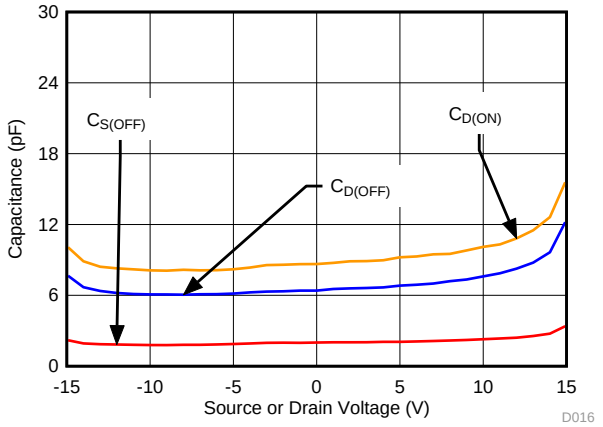
Typical Characteristics (continued)

at T_A = 25°C, V_{DD} = 15 V, and V_{SS} = –15 V (unless otherwise noted)



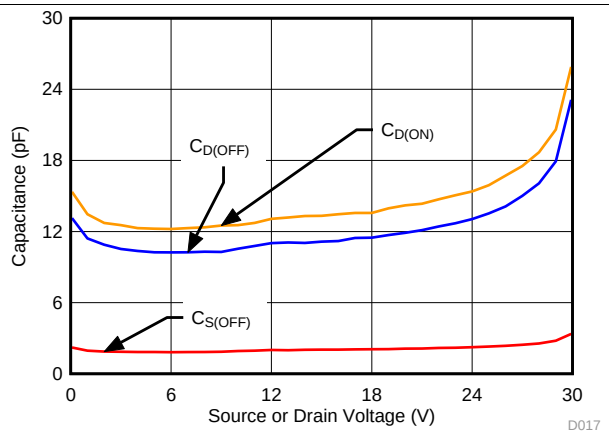
MUX506, V_{DD} = 15 V, V_{SS} = –15 V

Figure 19. Capacitance vs Source Voltage



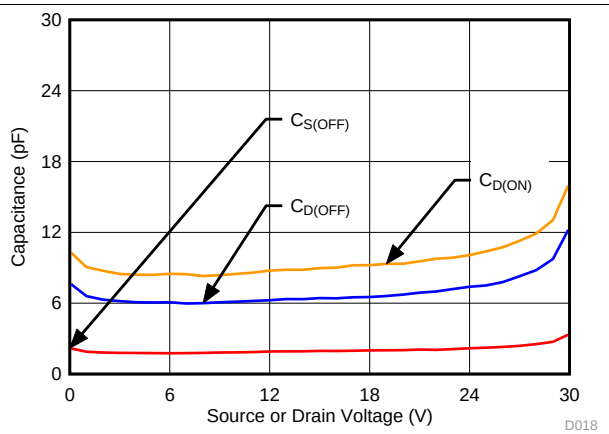
MUX507, V_{DD} = 15 V, V_{SS} = –15 V

Figure 20. Capacitance vs Source Voltage



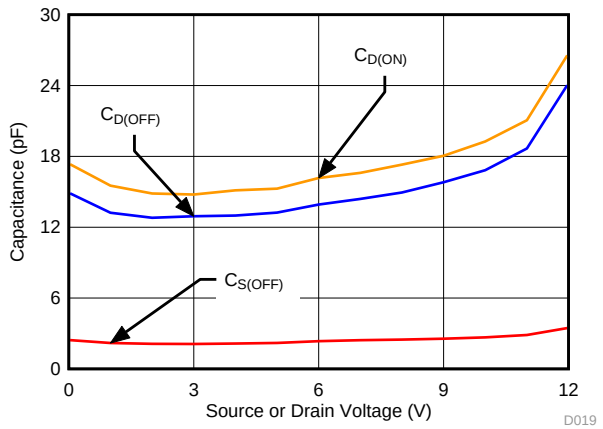
MUX506, V_{DD} = 30 V, V_{SS} = 0 V

Figure 21. Capacitance vs Source Voltage



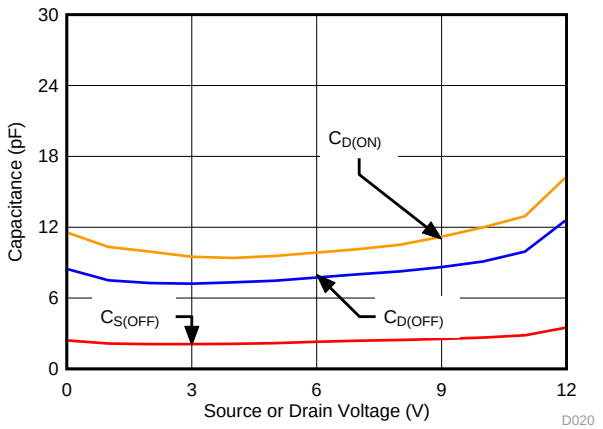
MUX507, V_{DD} = 30 V, V_{SS} = 0 V

Figure 22. Capacitance vs Source Voltage



MUX506, V_{DD} = 12 V, V_{SS} = 0 V

Figure 23. Capacitance vs Source Voltage



MUX507, V_{DD} = 12 V, V_{SS} = 0 V

Figure 24. Capacitance vs Source Voltage

Typical Characteristics (continued)

at T_A = 25°C, V_{DD} = 15 V, and V_{SS} = –15 V (unless otherwise noted)

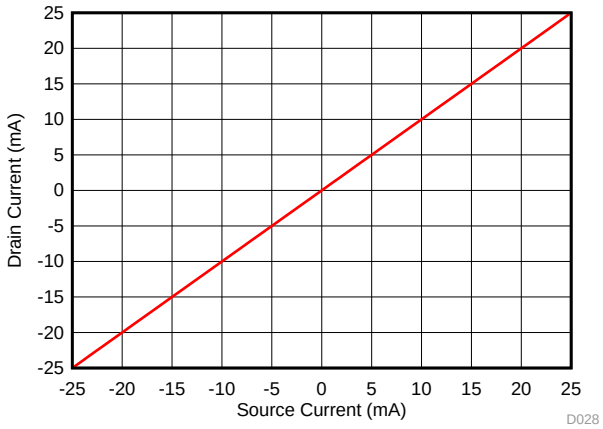


Figure 25. Source Current vs Drain Current

7 Parameter Measurement Information

7.1 Truth Tables

Table 1. MUX506

EN	A3	A2	A1	A0	ON-CHANNEL
0	X(1)	X(1)	X(1)	X(1)	All channels are off
1	0	0	0	0	Channel 1
1	0	0	0	1	Channel 2
1	0	0	1	0	Channel 3
1	0	0	1	1	Channel 4
1	0	1	0	0	Channel 5
1	0	1	0	1	Channel 6
1	0	1	1	0	Channel 7
1	0	1	1	1	Channel 8
1	1	0	0	0	Channel 9
1	1	0	0	1	Channel 10
1	1	0	1	0	Channel 11
1	1	0	1	1	Channel 12
1	1	1	0	0	Channel 13
1	1	1	0	1	Channel 14
1	1	1	1	0	Channel 15
1	1	1	1	1	Channel 16

(1) X denotes *don't care*..

Table 2. MUX507

EN	A2	A1	A0	ON-CHANNEL
0	X(1)	X(1)	X(1)	All channels are off
1	0	0	0	Channels 1A and 1B
1	0	0	1	Channels 2A and 2B
1	0	1	0	Channels 3A and 3B
1	0	1	1	Channels 4A and 4B
1	1	0	0	Channels 5A and 5B
1	1	0	1	Channels 6A and 6B
1	1	1	0	Channels 7A and 7B
1	1	1	1	Channels 8A and 8B

(1) X denotes *don't care*.

7.2 On-Resistance

The on-resistance of the MUX50x is the ohmic resistance across the source (Sx, SxA, or SxB) and drain (D, DA, or DB) pins of the device. The on-resistance varies with input voltage and supply voltage. The symbol R_{ON} is used to denote on-resistance. The measurement setup used to measure R_{ON} is shown in Figure 26. Voltage (V) and current (I_{CH}) are measured using this setup, and R_{ON} is computed as shown in Equation 1:

$$R_{ON} = V / I_{CH} \quad (1)$$

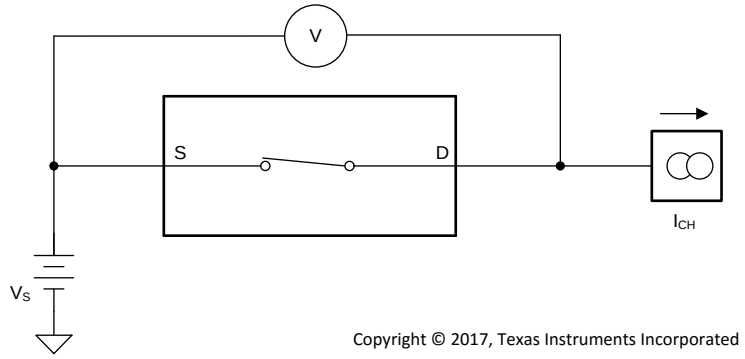


Figure 26. On-Resistance Measurement Setup

7.3 Off Leakage

There are two types of leakage currents associated with a switch during the OFF state:

1. Source off-leakage current
2. Drain off-leakage current

Source leakage current is defined as the leakage current flowing into or out of the source pin when the switch is off. This current is denoted by the symbol $I_{S(OFF)}$.

Drain leakage current is defined as the leakage current flowing into or out of the drain pin when the switch is off. This current is denoted by the symbol $I_{D(OFF)}$.

The setup used to measure both off-leakage currents is shown in Figure 27

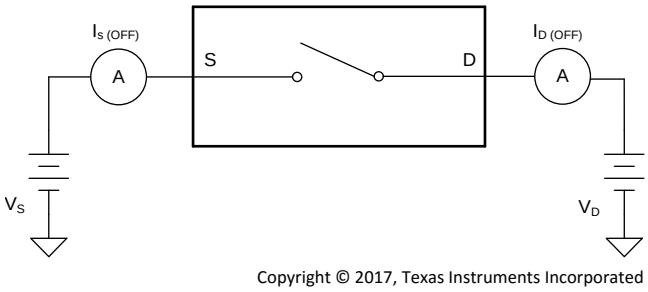


Figure 27. Off-Leakage Measurement Setup

7.4 On-Leakage Current

On-leakage current is defined as the leakage current that flows into or out of the drain pin when the switch is in the ON state. The source pin is left floating during the measurement. Figure 28 shows the circuit used for measuring the on-leakage current, denoted by $I_{D(ON)}$.

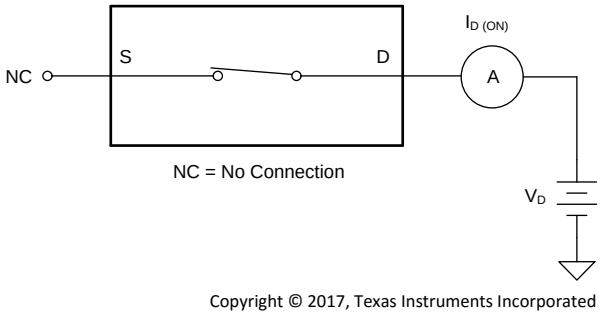


Figure 28. On-Leakage Measurement Setup

7.5 Transition Time

Transition time is defined as the time taken by the output of the MUX50x to rise or fall to 90% of the transition after the digital address signal has fallen or risen to 50% of the transition. Figure 29 shows the setup used to measure transition time, denoted by the symbol t_t.

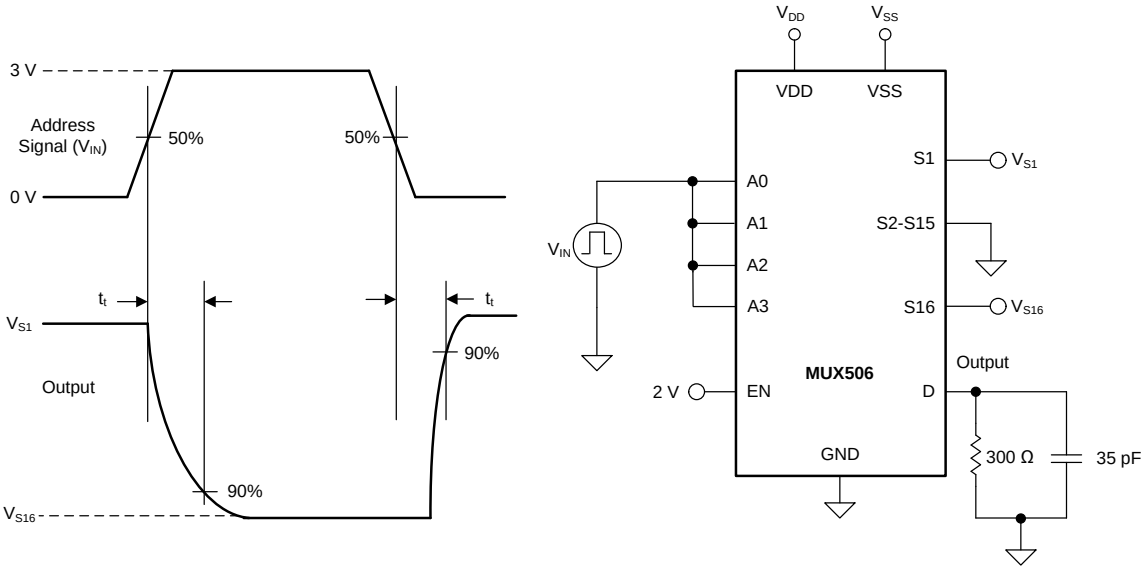


Figure 29. Transition-Time Measurement Setup

7.6 Break-Before-Make Delay

Break-before-make delay is a safety feature that prevents two inputs from connecting when the MUX50x is switching. The MUX50x output first breaks from the ON-state switch before making the connection with the next ON-state switch. The time delay between the *break* and the *make* is known as break-before-make delay. Figure 30 shows the setup used to measure break-before-make delay, denoted by the symbol t_{BBM}.

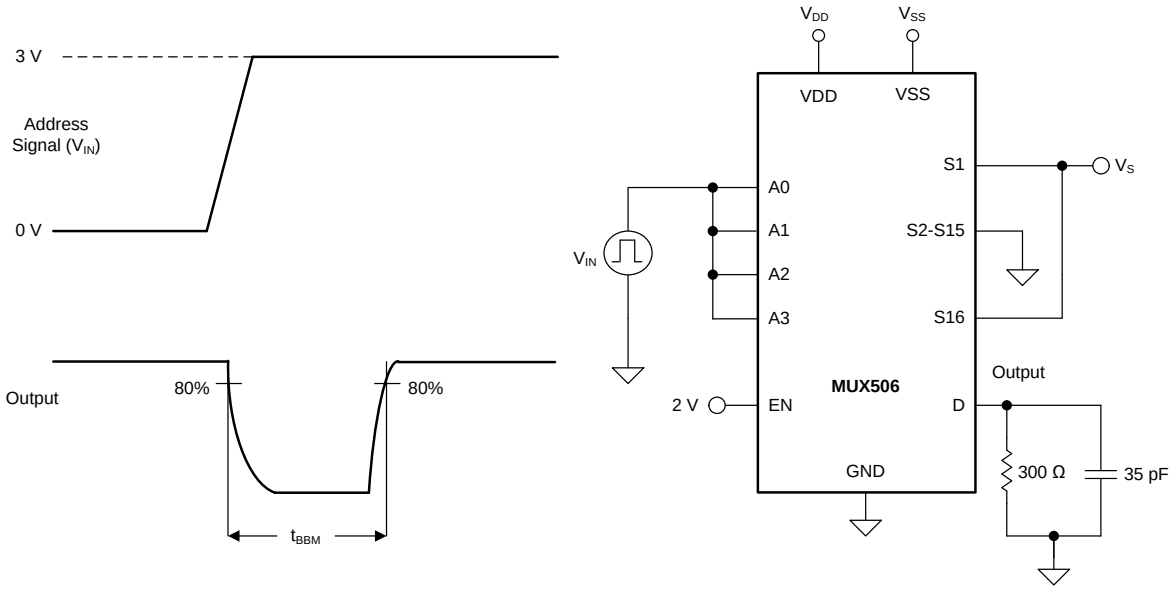


Figure 30. Break-Before-Make Delay Measurement Setup

7.7 Turn-On and Turn-Off Time

Turn-on time is defined as the time taken by the output of the MUX50x to rise to 90% final value after the enable signal has risen to 50% final value. Figure 31 shows the setup used to measure turn-on time. Turn-on time is denoted by the symbol t_{ON}.

Turn off time is defined as the time taken by the output of the MUX50x to fall to 10% initial value after the enable signal has fallen to 50% initial value. Figure 31 shows the setup used to measure turn-off time. Turn-off time is denoted by the symbol t_{OFF}.

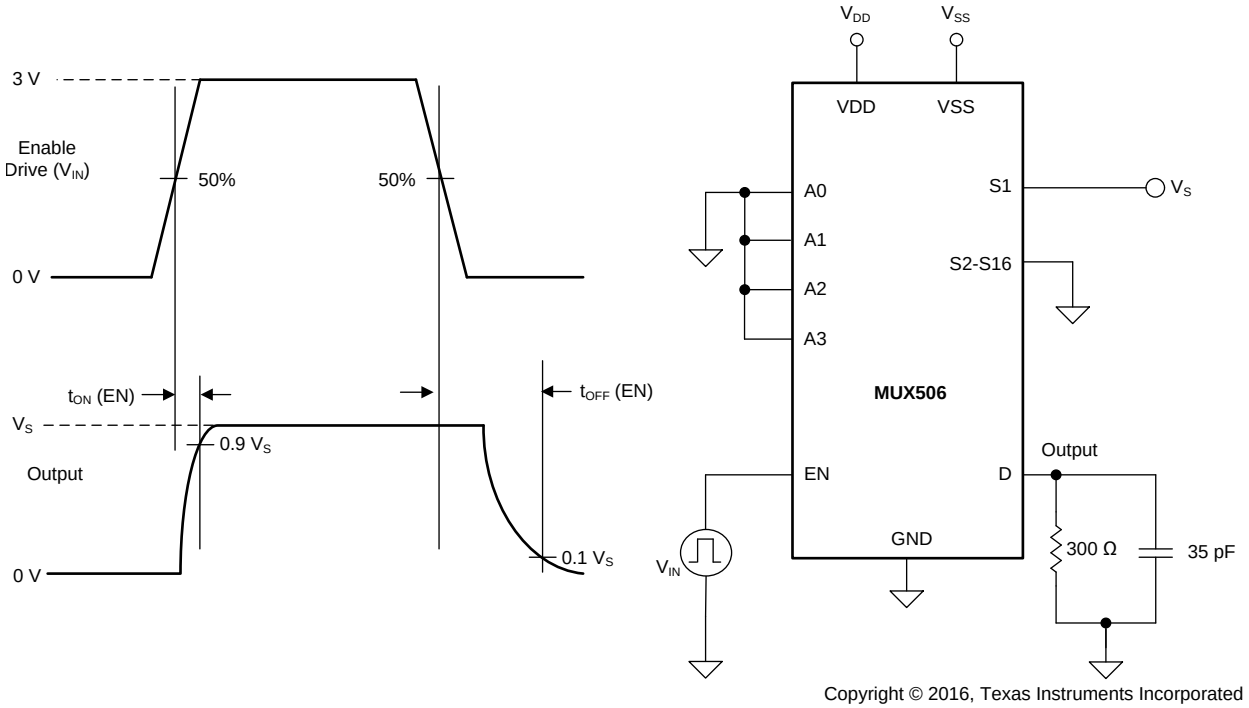


Figure 31. Turn-On and Turn-Off Time Measurement Setup

7.8 Charge Injection

The MUX50x have a simple transmission-gate topology. Any mismatch in capacitance between the NMOS and PMOS transistors results in a charge injected into the drain or source during the falling or rising edge of the gate signal. The amount of charge injected into the source or drain of the device is known as charge injection, and is denoted by the symbol Q_{INJ}. Figure 32 shows the setup used to measure charge injection.

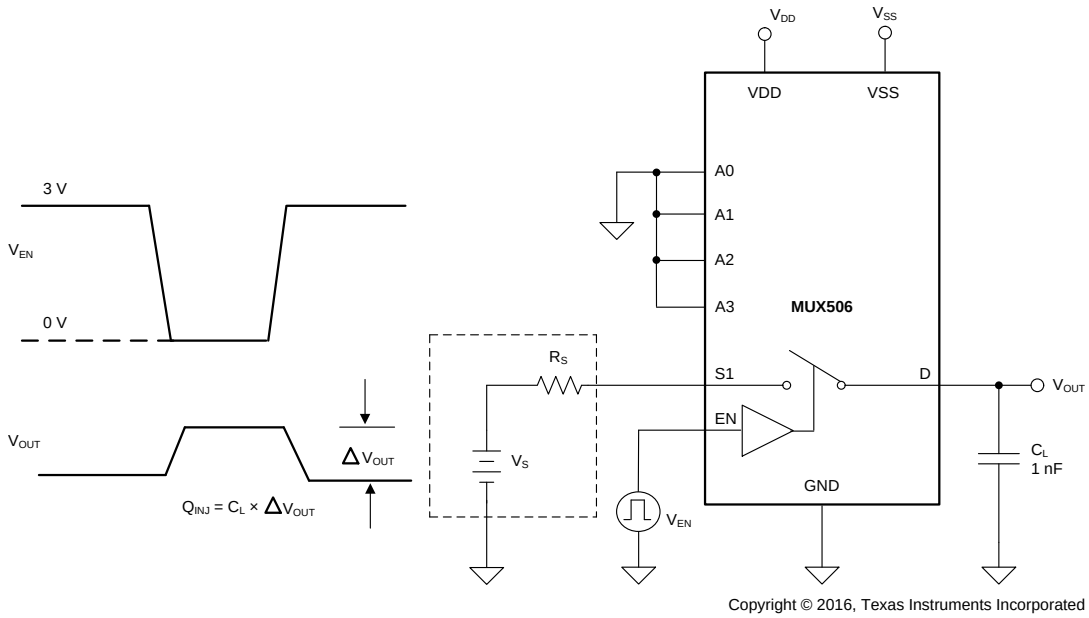


Figure 32. Charge-Injection Measurement Setup

7.9 Off Isolation

Off isolation is defined as the voltage at the drain pin (D, DA, or DB) of the MUX50x when a 1-V_{RMS} signal is applied to the source pin (Sx, SxA, or SxB) of an off-channel. Figure 33 shows the setup used to measure off isolation. Use Equation 2 to compute off isolation.

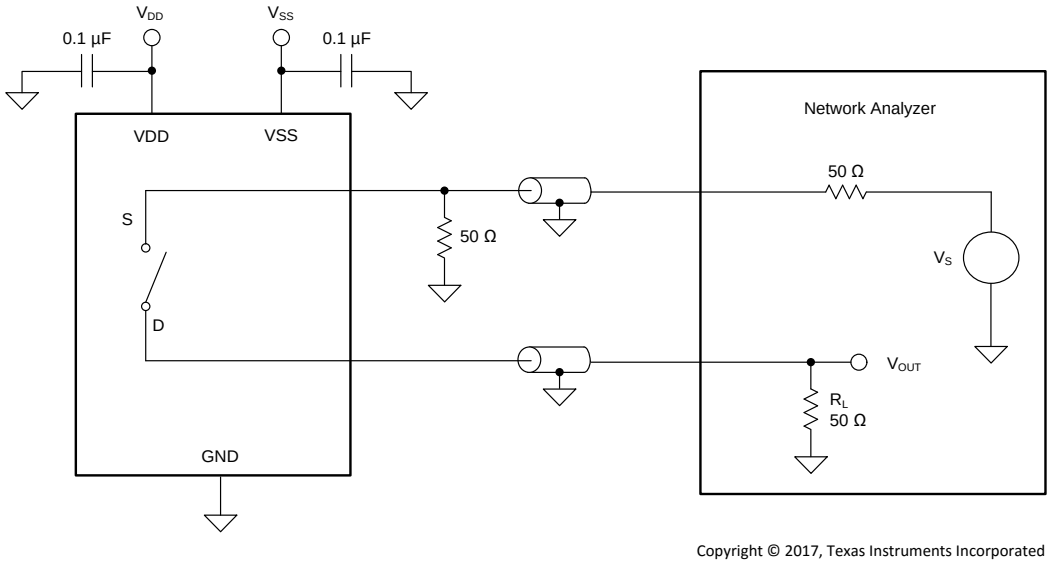


Figure 33. Off Isolation Measurement Setup

$$\text{Off Isolation} = 20 \cdot \text{Log}\left(\frac{V_{OUT}}{V_S}\right) \quad (2)$$

7.10 Channel-to-Channel Crosstalk

Channel-to-channel crosstalk is defined as the voltage at the source pin (Sx, SxA, or SxB) of an off-channel, when a 1-V_{RMS} signal is applied at the source pin of an on-channel. Figure 34 shows the setup used to measure channel-to-channel crosstalk. Use Equation 3 to compute, channel-to-channel crosstalk.

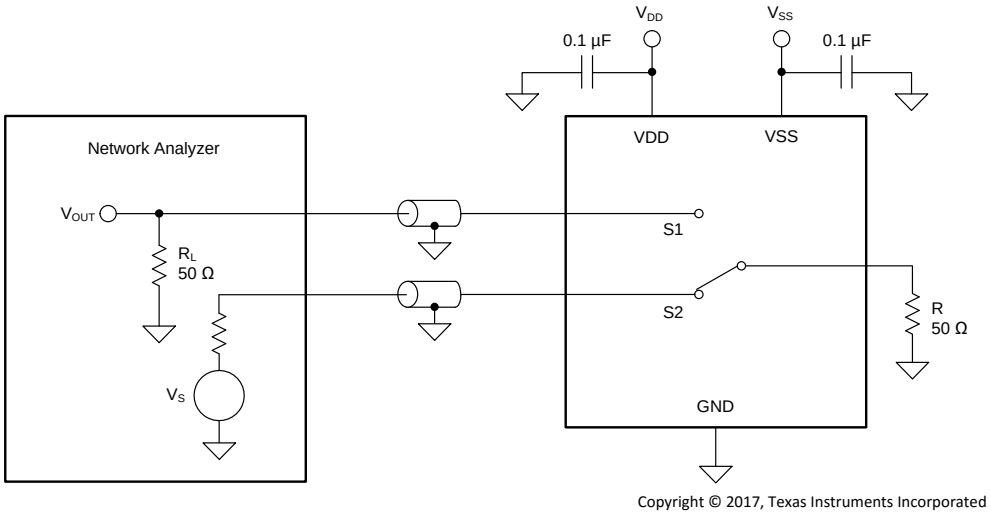


Figure 34. Channel-to-Channel Crosstalk Measurement Setup

$$\text{Channel-to-Channel Crosstalk} = 20 \cdot \text{Log}\left(\frac{V_{OUT}}{V_S}\right) \quad (3)$$

7.11 Bandwidth

Bandwidth is defined as the range of frequencies that are attenuated by less than 3 dB when the input is applied to the source pin of an on-channel, and the output measured at the drain pin of the MUX50x. Figure 35 shows the setup used to measure bandwidth of the mux. Use Equation 4 to compute the attenuation.

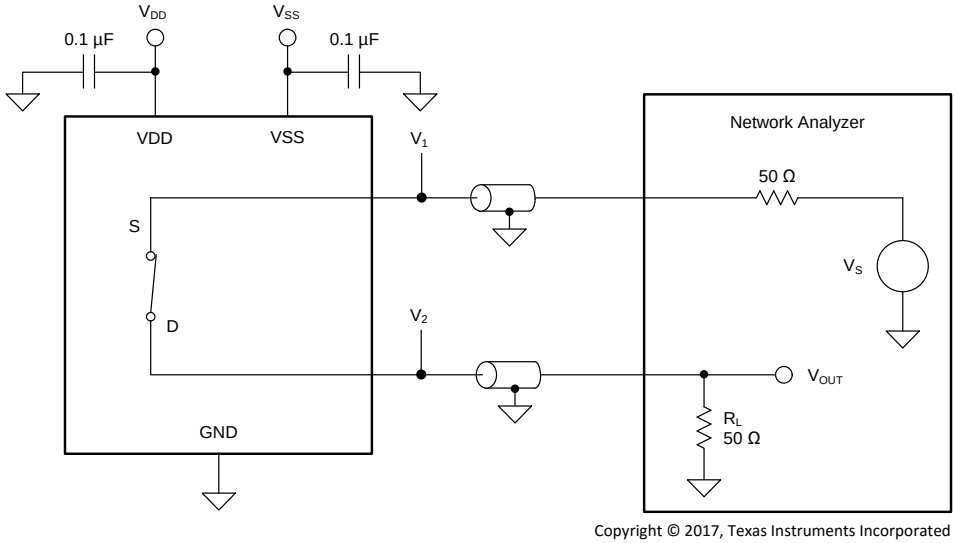


Figure 35. Bandwidth Measurement Setup

$$\text{Attenuation} = 20 \cdot \text{Log}\left(\frac{V_2}{V_1}\right) \quad (4)$$

7.12 THD + Noise

The total harmonic distortion (THD) of a signal is a measurement of the harmonic distortion, and is defined as the ratio of the sum of the powers of all harmonic components to the power of the fundamental frequency at the mux output. The on-resistance of the MUX50x varies with the amplitude of the input signal and results in distortion when the drain pin is connected to a low-impedance load. Total harmonic distortion plus noise is denoted as THD+N. Figure 36 shows the setup used to measure THD+N of the MUX50x.

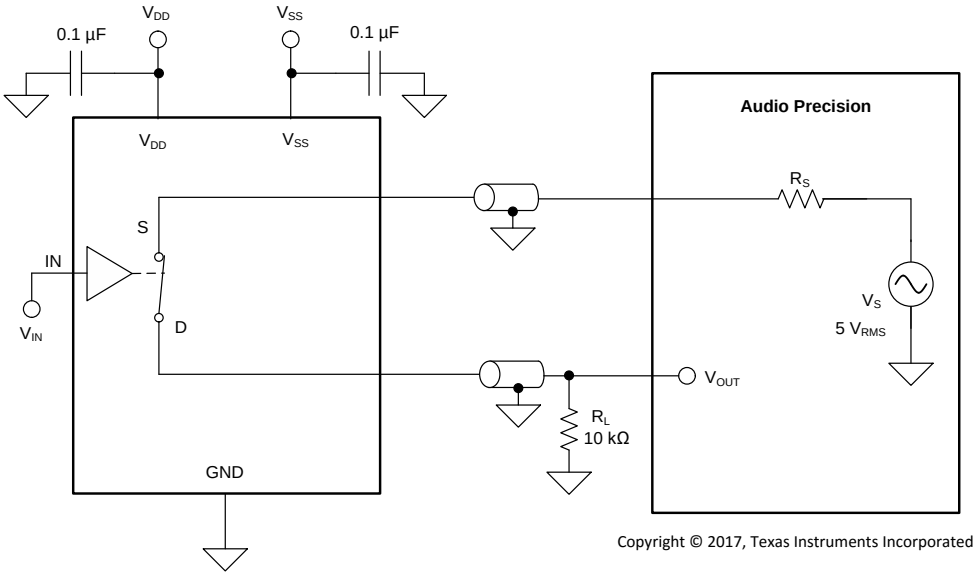


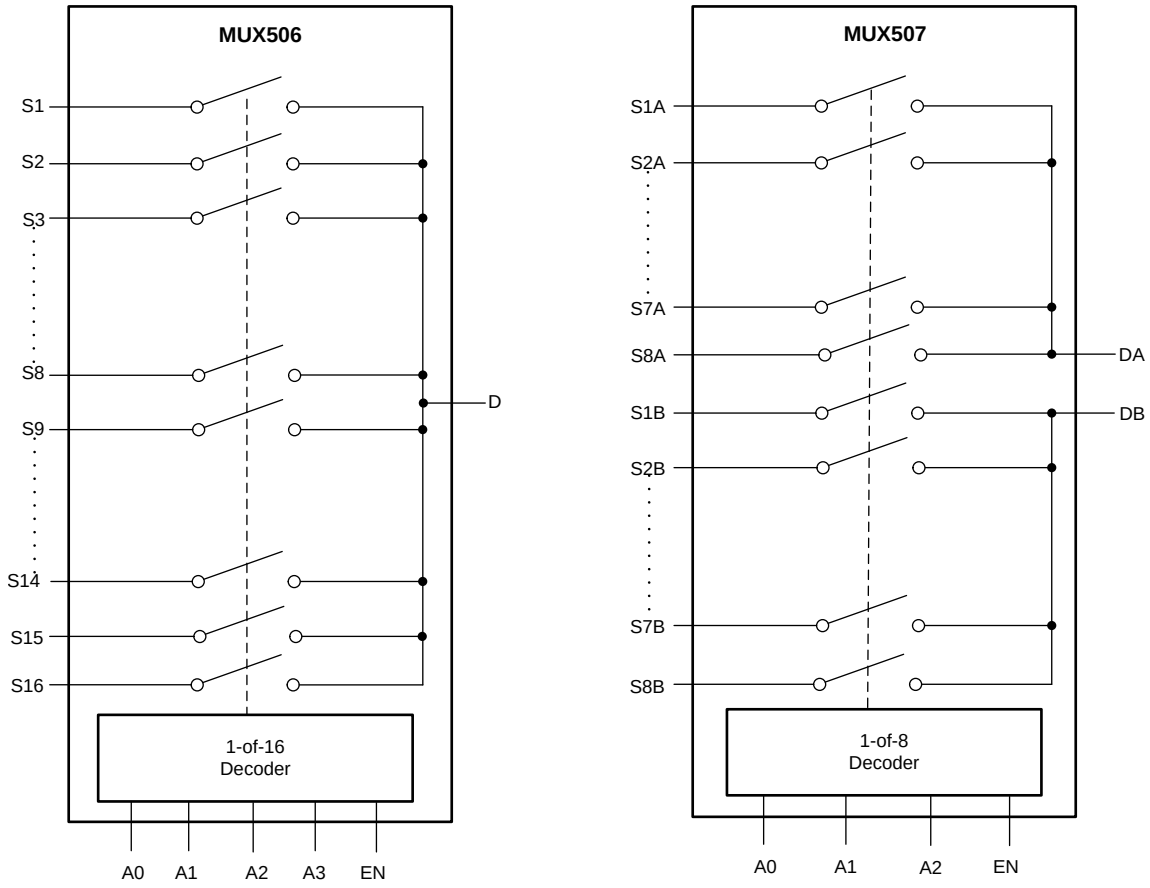
Figure 36. THD+N Measurement Setup

8 Detailed Description

8.1 Overview

The MUX50x are a family of analog multiplexers. The *Functional Block Diagram* section provides a top-level block diagram of both the MUX506 and MUX507. The MUX506 is a 16-channel, single-ended, analog mux. The MUX507 is an 8-channel, differential or dual 8:1, single-ended, analog mux. Each channel is turned on or turned off based on the state of the address lines and enable pin.

8.2 Functional Block Diagram



8.3 Feature Description

8.3.1 Ultralow Leakage Current

The MUX50x provide extremely low on- and off-leakage currents. The MUX50x are capable of switching signals from high source-impedance inputs into a high input-impedance op amp with minimal offset error because of the ultra-low leakage currents. Figure 37 shows typical leakage currents of the MUX50x versus temperature.

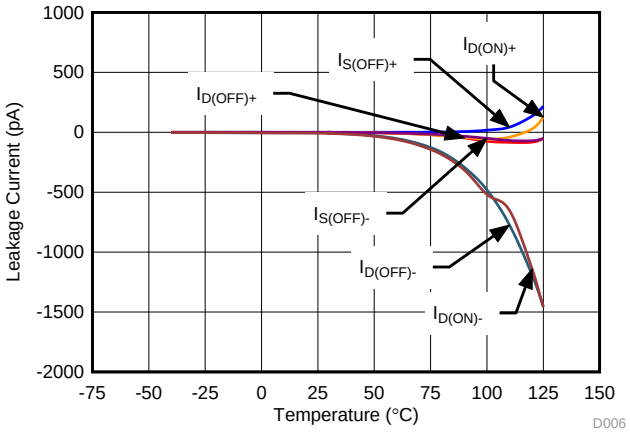


Figure 37. Leakage Current vs Temperature

8.3.2 Ultralow Charge Injection

The MUX50x have a simple transmission gate topology, as shown in Figure 38. Any mismatch in the stray capacitance associated with the NMOS and PMOS causes an output level change whenever the switch is opened or closed.

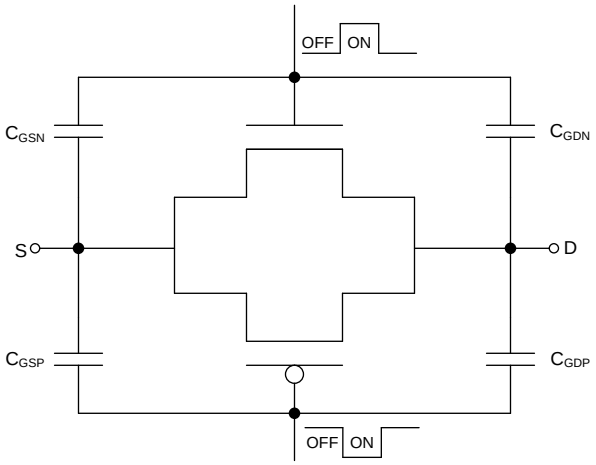


Figure 38. Transmission Gate Topology

Feature Description (continued)

The MUX50x have special charge-injection cancellation circuitry that reduces the source-to-drain charge injection to as low as 0.31 pC at V_S = 0 V, and ±0.9 pC in the full signal range, as shown in Figure 39.

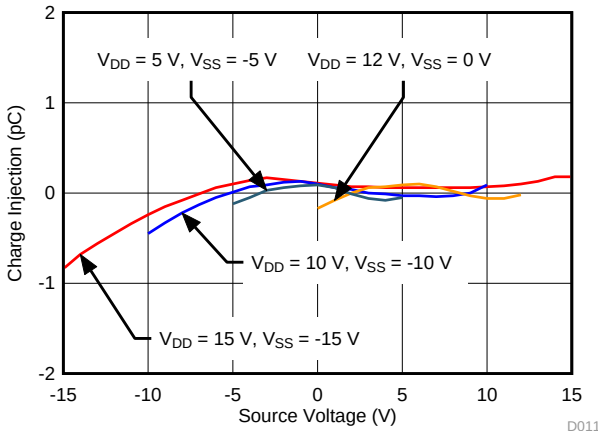


Figure 39. Source-to-Drain Charge Injection

The drain-to-source charge injection becomes important when the device is used as a demultiplexer (demux), where D becomes the input and Sx becomes the output. Figure 40 shows the drain-to-source charge injection across the full signal range.

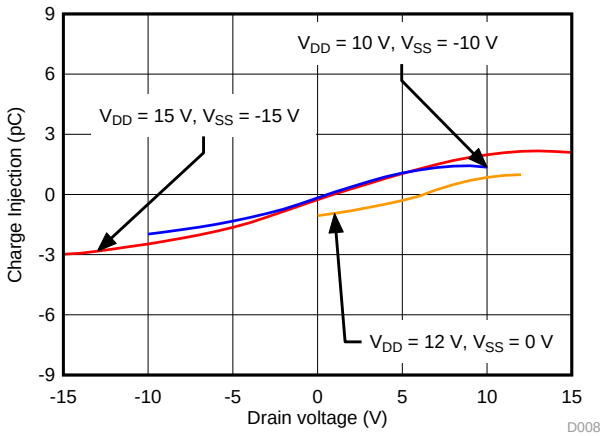


Figure 40. Drain-to-Source Charge Injection

Feature Description (continued)

8.3.3 Bidirectional Operation

The MUX50x are operable as both a mux and demux. The source (Sx, SxA, SxB) and drain (D, DA, DB) pins of the MUX50x are used either as input or output. Each MUX50x channel has very similar characteristics in both directions.

8.3.4 Rail-to-Rail Operation

The valid analog signal for the MUX50x ranges from V_{SS} to V_{DD}. The input signal to the MUX50x swings from V_{SS} to V_{DD} without any significant degradation in performance. The on-resistance of the MUX50x varies with input signal, as shown in Figure 41

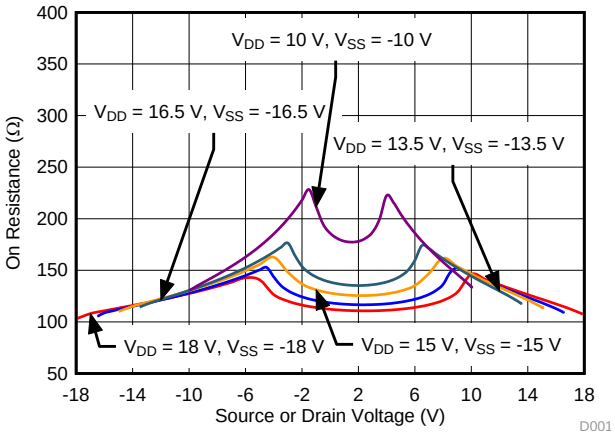


Figure 41. On-resistance vs Source or Drain Voltage

8.4 Device Functional Modes

When the EN pin of the MUX50x is pulled high, one of the switches is closed based on the state of the address lines. When the EN pin is pulled low, all the switches are in an open state irrespective of the state of the address lines. The EN pin can be connected to V_{DD} (as high as 36 V).

9 Application and Implementation

NOTE

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

9.1 Application Information

The MUX50x family offers outstanding input/output leakage currents and ultra-low charge injection. These devices operate up to 36 V, and offer true rail-to-rail input and output. The on-capacitance of the MUX50x is very low. These features makes the MUX50x a family of precision, robust, high-performance analog multiplexer for high-voltage, industrial applications.

9.2 Typical Application

Figure 42 shows a 16-bit, differential, 8-channel, multiplexed, data-acquisition system. This example is typical in industrial applications that require low distortion and a high-voltage differential input. The circuit uses the ADS8864, a 16-bit, 400-kSPS successive-approximation-resistor (SAR) analog-to-digital converter (ADC), along with a precision, high-voltage, signal-conditioning front end, and a 4-channel differential mux. This TI Precision Design details the process for optimizing the precision, high-voltage, front-end drive circuit using the MUX507, OPA192 and OPA140 to achieve excellent dynamic performance and linearity with the ADS8864.

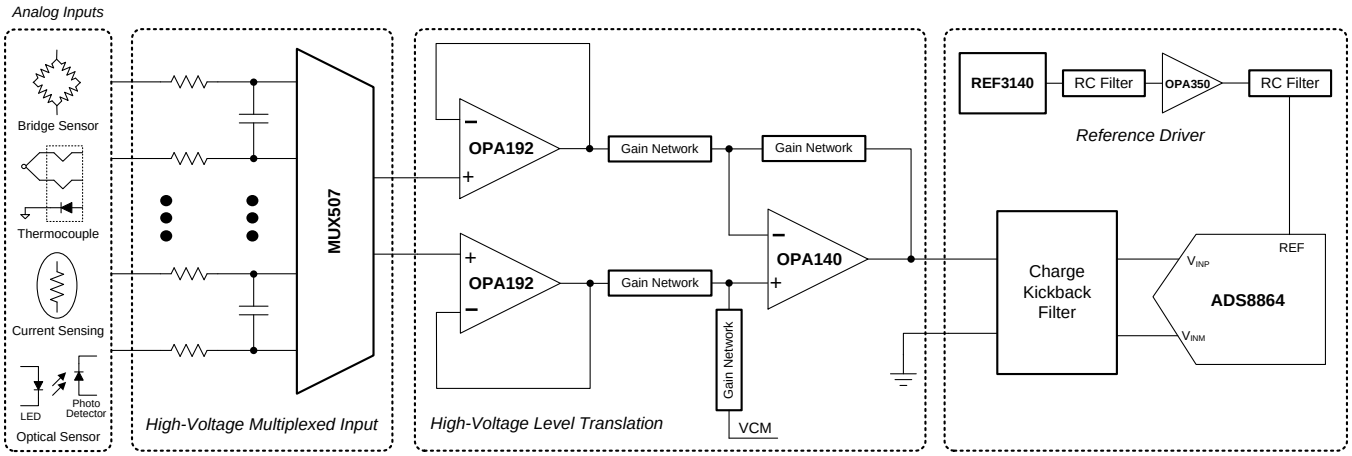


Figure 42. 16-Bit Precision Multiplexed Data-Acquisition System for High-Voltage Inputs With Lowest Distortion

9.2.1 Design Requirements

The primary objective is to design a ±20 V, differential, 8-channel, multiplexed, data-acquisition system with lowest distortion using the 16-bit ADS8864 at a throughput of 400 kSPS for a 10-kHz, full-scale, pure, sine-wave input. The design requirements for this block design are:

- System supply voltage: ±15 V
- ADC supply voltage: 3.3 V
- ADC sampling rate: 400 kSPS
- ADC reference voltage (REFP): 4.096 V
- System input signal: A high-voltage differential input signal with a peak amplitude of 20 V and frequency (f_{IN}) of 10 kHz are applied to each differential input of the mux.

Typical Application (continued)

9.2.2 Detailed Design Procedure

The purpose of this precision design is to design an optimal, high-voltage, multiplexed, data-acquisition system for highest system linearity and fast settling. The overall system block diagram is illustrated in Figure 42. The circuit is a multichannel, data-acquisition signal chain consisting of an input low-pass filter, mux, mux output buffer, attenuating SAR ADC driver, and the reference driver. The architecture allows fast sampling of multiple channels using a single ADC, providing a low-cost solution. This design systematically approaches each analog circuit block to achieve a 16-bit settling for a full-scale input stage voltage and linearity for a 10-kHz sinusoidal input signal at each input channel. Detailed design considerations and component selection procedure can be found in the TI Precision Design TIPD151, *16-Bit, 400-kSPS, 4-Channel Multiplexed Data-Acquisition System for High-Voltage Inputs with Lowest Distortion*.

9.2.3 Application Curve

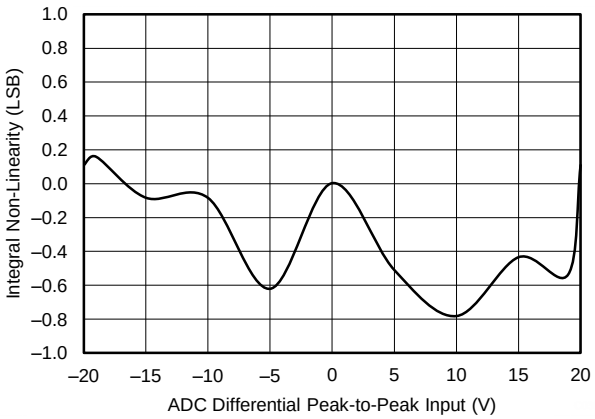


Figure 43. ADC 16-Bit Linearity Error for the Multiplexed Data-Acquisition Block

10 Power Supply Recommendations

The MUX50x operates across a wide supply range of ±5 V to ±18 V (10 V to 36 V in single-supply mode). The devices also perform well with unsymmetric supplies such as V_{DD} = 12 V and V_{SS}= –5 V. For reliable operation, use a supply decoupling capacitor ranging between 0.1 µF to 10 µF at both the VDD and VSS pins to ground.

The on-resistance of the MUX50x varies with supply voltage, as illustrated in Figure 44

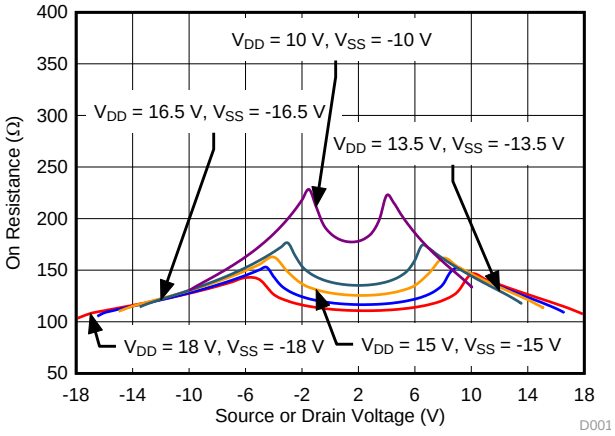


Figure 44. On-Resistance Variation With Supply and Input Voltage

11 Layout

11.1 Layout Guidelines

Figure 45 illustrates an example of a PCB layout with the MUX506IPW, and Figure 46 illustrates an example of a PCB layout with MUX507IPW.

Some key considerations are:

1. Decouple the VDD and VSS pins with a 0.1-µF capacitor, placed as close to the pin as possible. Make sure that the capacitor voltage rating is sufficient for the V_{DD} and V_{SS} supplies.
2. Keep the input lines as short as possible. In case of the differential signal, make sure the A inputs and B inputs are as symmetric as possible.
3. Use a solid ground plane to help distribute heat and reduce electromagnetic interference (EMI) noise pickup.
4. Do not run sensitive analog traces in parallel with digital traces. Avoid crossing digital and analog traces if possible, and only make perpendicular crossings when necessary.

11.2 Layout Example

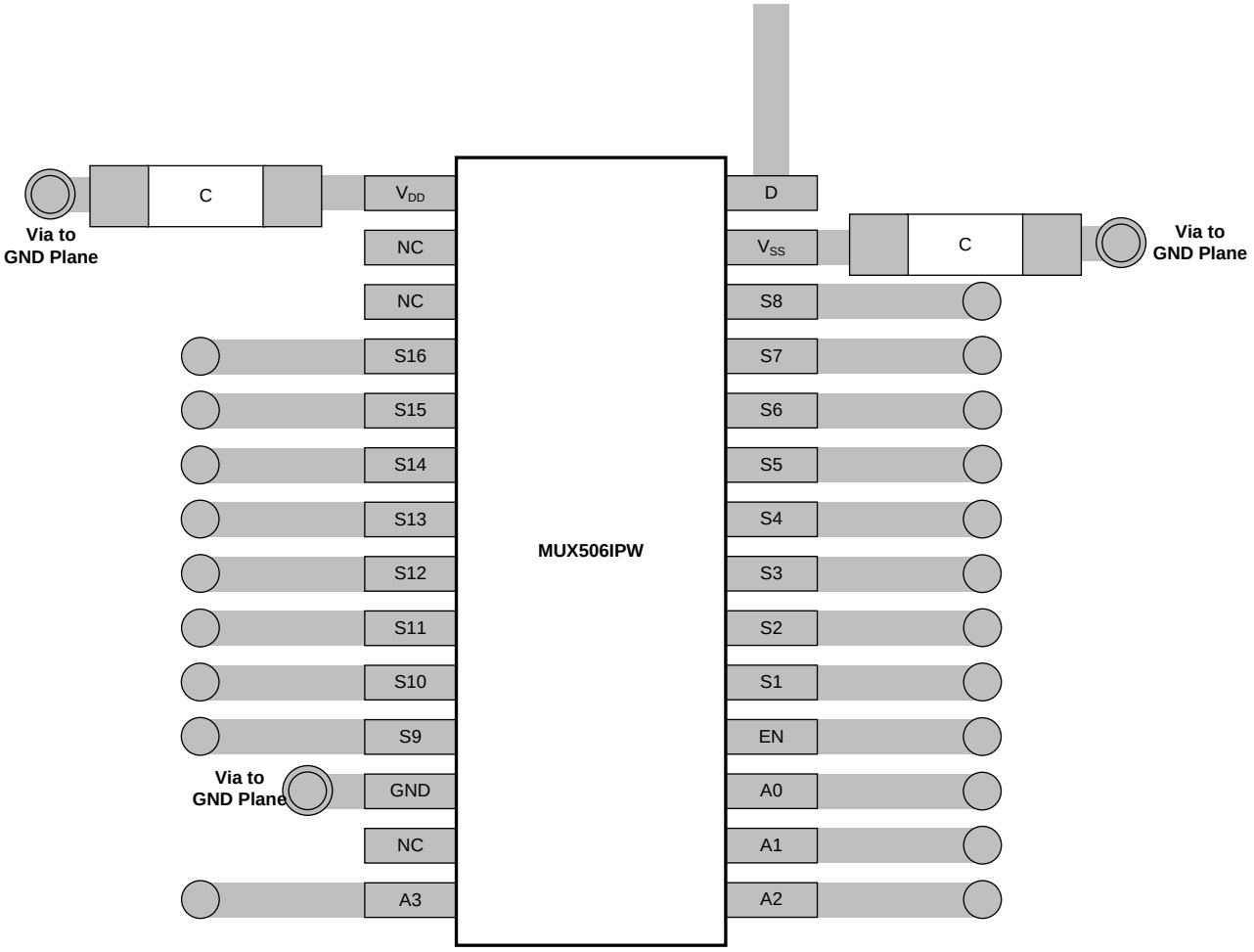


Figure 45. MUX506IPW Layout Example

Layout Example (continued)

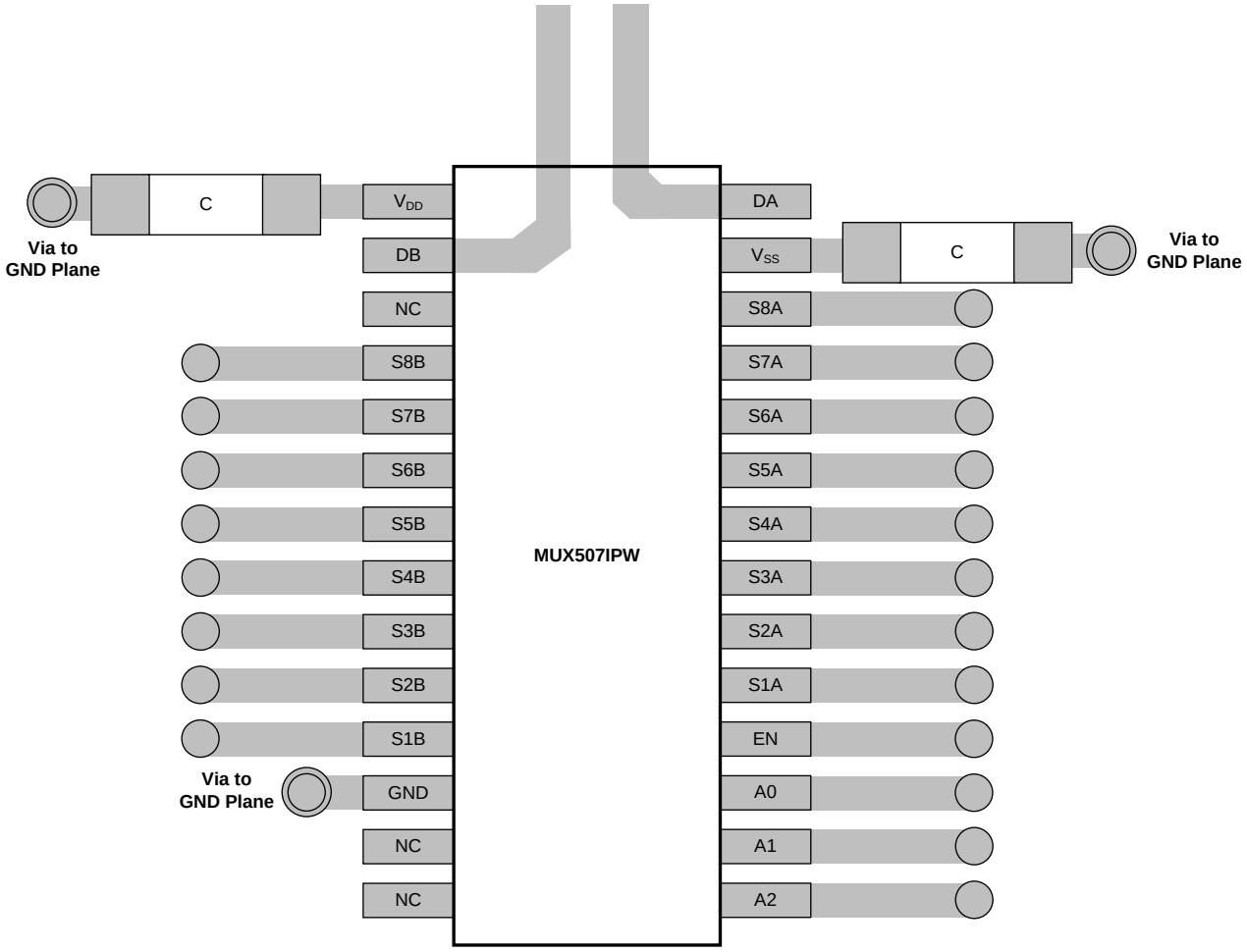


Figure 46. MUX507IPW Layout Example

12 Device and Documentation Support

12.1 Documentation Support

12.1.1 Related Documentation

For related documentation see the following:

- *ADS8864 16-Bit, 400-kSPS, Serial Interface, microPower, Miniature, Single-Ended Input, SAR Analog-to-Digital Converter* (SBAS572)
- *OPAx192 36-V, Precision, Rail-to-Rail Input/Output, Low Offset Voltage, Low Input Bias Current Op Amp with e-trim* (SBOS620)
- *OPAx140 High-Precision, Low-Noise, Rail-to-Rail Output, 11-MHz JFET Op Amp* (SBOS498)

12.2 Related Links

The following table lists quick access links. Categories include technical documents, support and community resources, tools and software, and quick access to sample or buy.

Table 3. Related Links

PARTS	PRODUCT FOLDER	SAMPLE & BUY	TECHNICAL DOCUMENTS	TOOLS & SOFTWARE	SUPPORT & COMMUNITY
MUX506	Click here	Click here	Click here	Click here	Click here
MUX507	Click here	Click here	Click here	Click here	Click here

12.3 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. In the upper right corner, click on *Alert me* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

12.4 Community Resources

The following links connect to TI community resources. Linked contents are provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

TI E2E™ Online Community ***TI's Engineer-to-Engineer (E2E) Community.*** Created to foster collaboration among engineers. At e2e.ti.com, you can ask questions, share knowledge, explore ideas and help solve problems with fellow engineers.

Design Support ***TI's Design Support*** Quickly find helpful E2E forums along with design support tools and contact information for technical support.

12.5 Trademarks

E2E is a trademark of Texas Instruments.
All other trademarks are the property of their respective owners.

12.6 Electrostatic Discharge Caution

This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

12.7 Glossary

SLYZ022 — *TI Glossary*.

This glossary lists and explains terms, acronyms, and definitions.

13 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead/Ball Finish (6)	MSL Peak Temp (3)	Op Temp (°C)	Device Marking (4/5)	Samples
MUX506IDWR	ACTIVE	SOIC	DW	28	1000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR	-40 to 125	MUX506DA	Samples
MUX506IPW	ACTIVE	TSSOP	PW	28	50	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR	-40 to 125	MUX506A	Samples
MUX506IPWR	ACTIVE	TSSOP	PW	28	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR	-40 to 125	MUX506A	Samples
MUX507IDWR	ACTIVE	SOIC	DW	28	1000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR	-40 to 125	MUX507DA	Samples
MUX507IPW	ACTIVE	TSSOP	PW	28	50	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR	-40 to 125	MUX507A	Samples
MUX507IPWR	ACTIVE	TSSOP	PW	28	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR	-40 to 125	MUX507A	Samples

(1) The marketing status values are defined as follows:
ACTIVE: Product device recommended for new designs.
LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.
NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.
PREVIEW: Device has been announced but is not in production. Samples may or may not be available.
OBSOLETE: TI has discontinued the production of the device.

(2) **RoHS:** TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".
RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.
Green: TI defines "Green" to mean the content of Chlorine (Cl) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

(3) MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

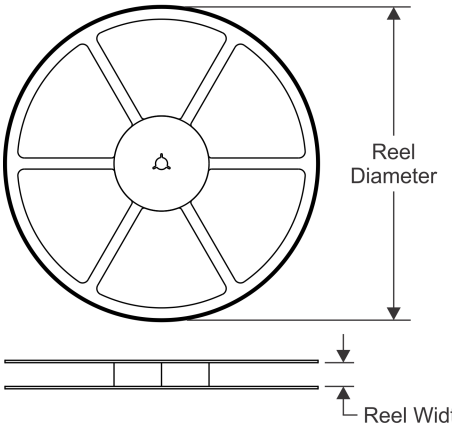
(4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

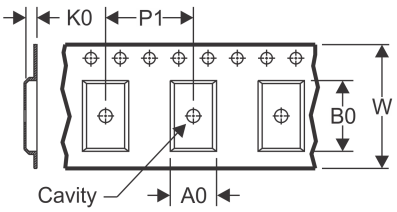
(6) Lead/Ball Finish - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.

TAPE AND REEL INFORMATION

REEL DIMENSIONS

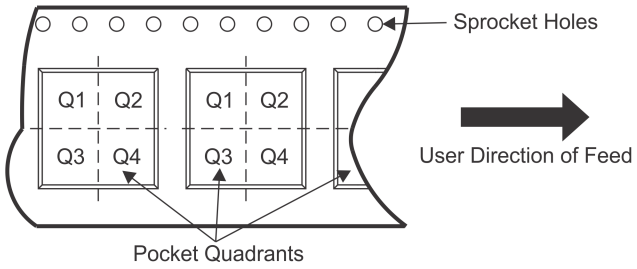


TAPE DIMENSIONS



A0	Dimension designed to accommodate the component width
B0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

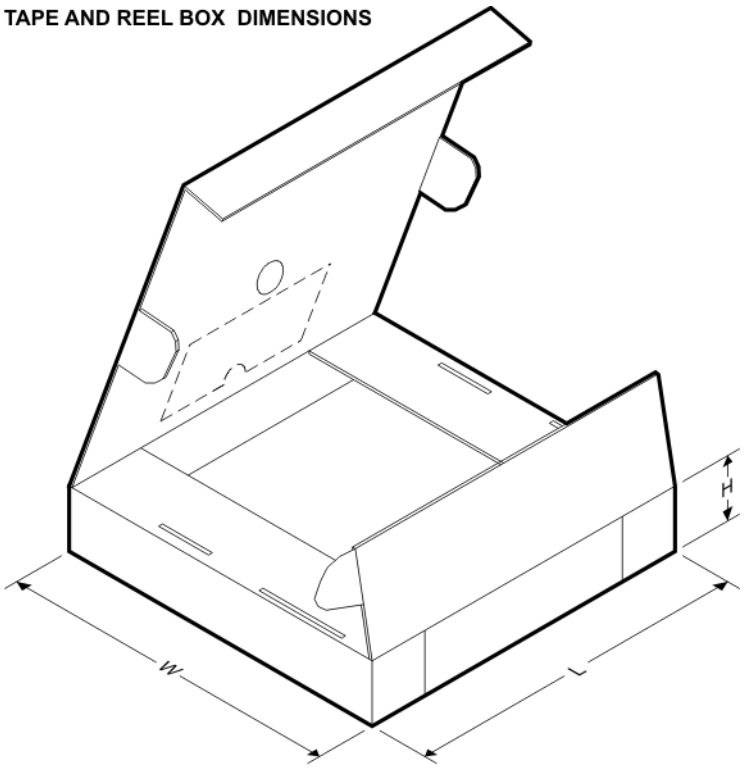
QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
MUX506IDWR	SOIC	DW	28	1000	330.0	32.4	11.35	18.67	3.1	16.0	32.0	Q1
MUX506IPWR	TSSOP	PW	28	2000	330.0	16.4	6.9	10.2	1.8	12.0	16.0	Q1
MUX507IDWR	SOIC	DW	28	1000	330.0	32.4	11.35	18.67	3.1	16.0	32.0	Q1
MUX507IPWR	TSSOP	PW	28	2000	330.0	16.4	6.9	10.2	1.8	12.0	16.0	Q1

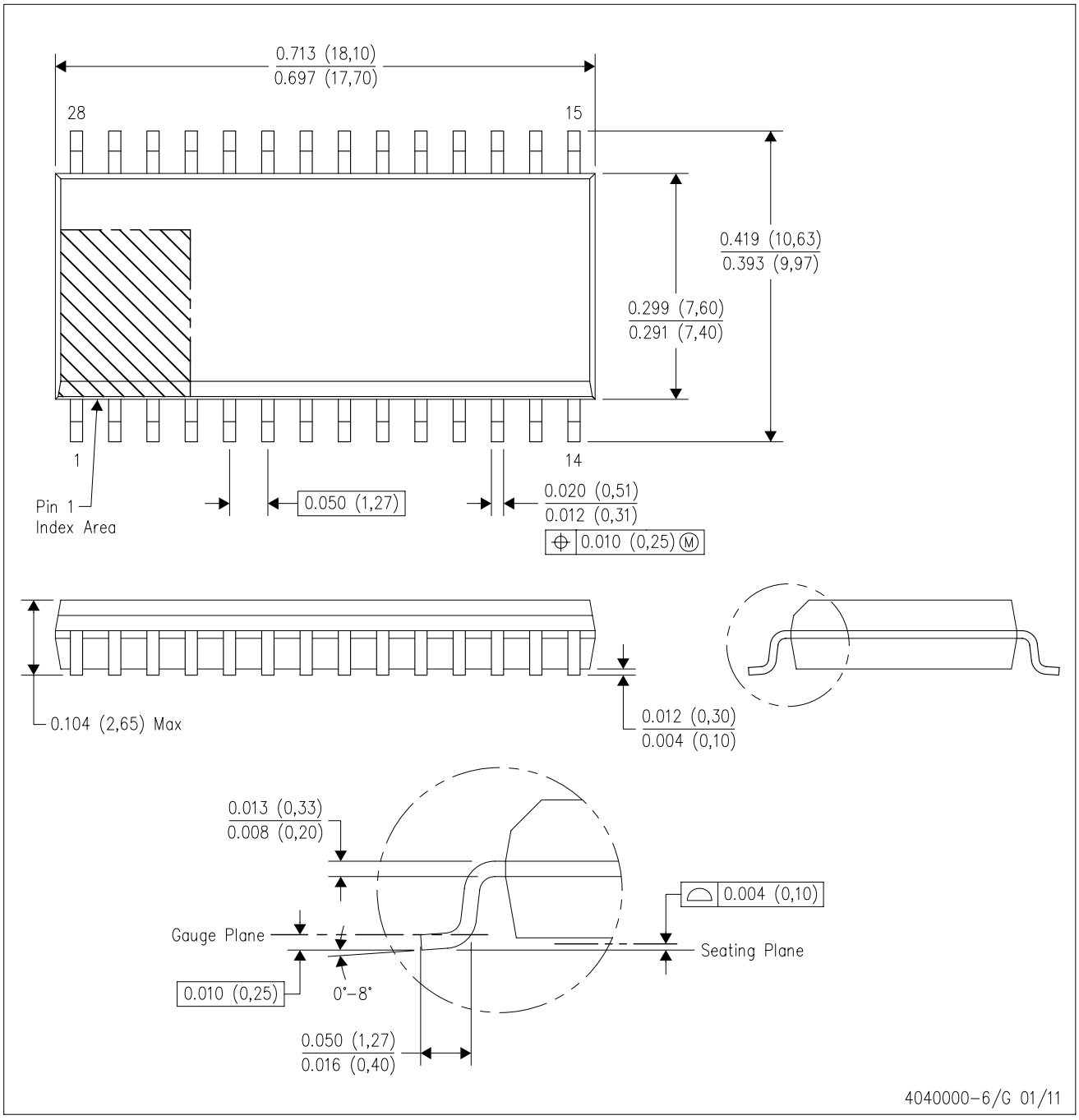
TAPE AND REEL BOX DIMENSIONS



*All dimensions are nominal

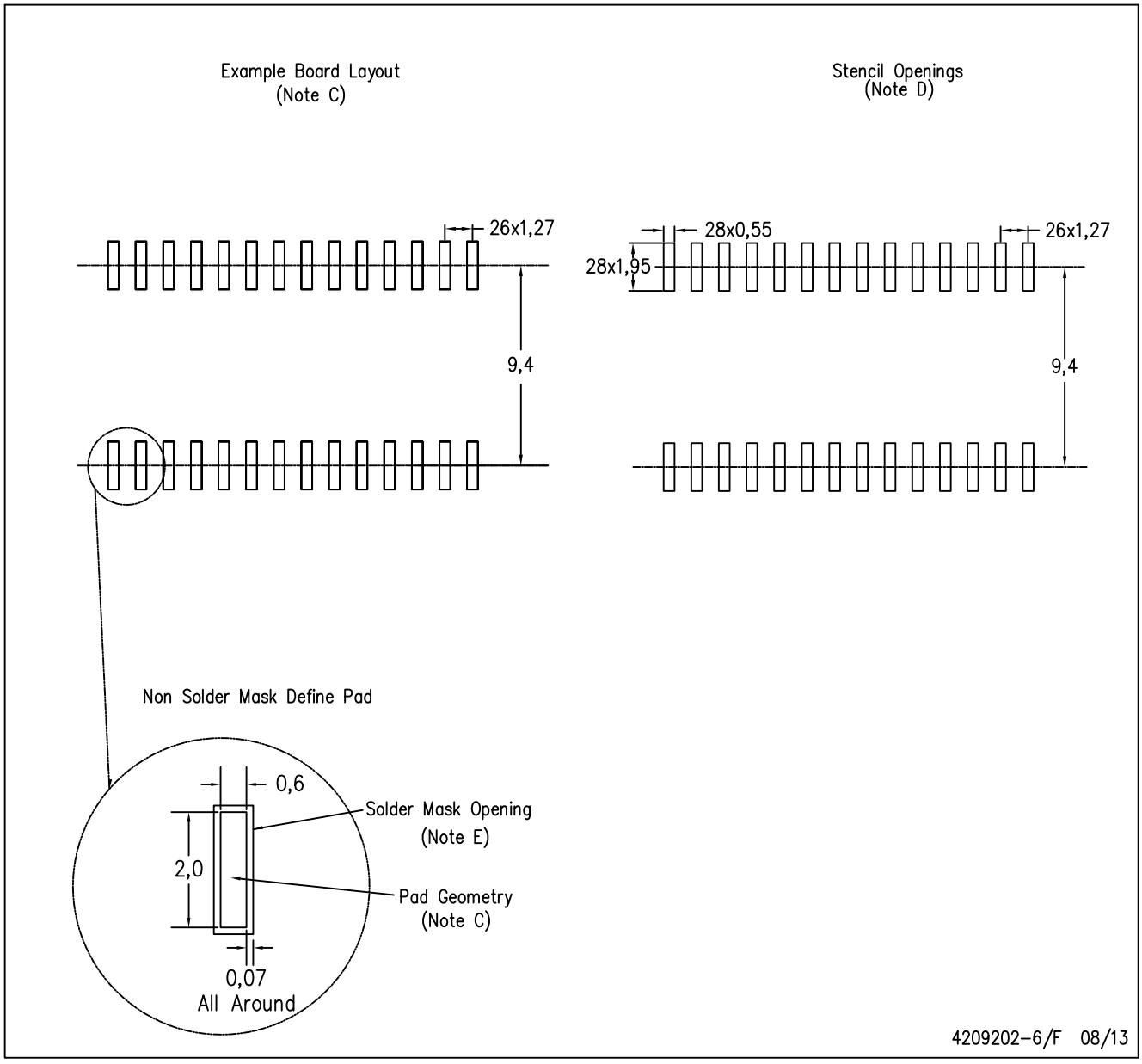
Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
MUX506IDWR	SOIC	DW	28	1000	367.0	367.0	55.0
MUX506IPWR	TSSOP	PW	28	2000	367.0	367.0	38.0
MUX507IDWR	SOIC	DW	28	1000	367.0	367.0	55.0
MUX507IPWR	TSSOP	PW	28	2000	367.0	367.0	38.0

DW (R–PDSO–G28) PLASTIC SMALL OUTLINE



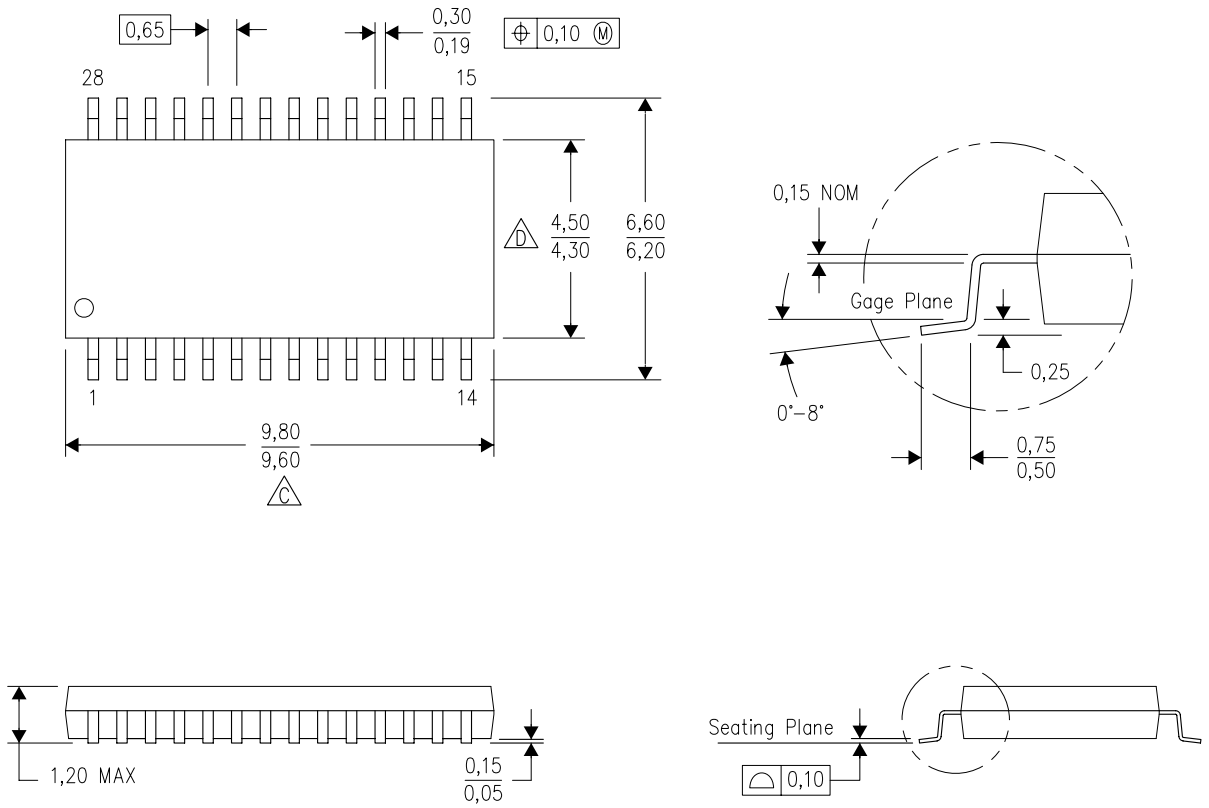
NOTES:
A. All linear dimensions are in inches (millimeters). Dimensioning and tolerancing per ASME Y14.5M–1994.
B. This drawing is subject to change without notice.
C. Body dimensions do not include mold flash or protrusion not to exceed 0.006 (0,15).
D. Falls within JEDEC MS–013 variation AE.

DW (R–PDSO–G28) PLASTIC SMALL OUTLINE



NOTES:
A. All linear dimensions are in millimeters.
B. This drawing is subject to change without notice.
C. Refer to IPC7351 for alternate board design.
D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC–7525
E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.

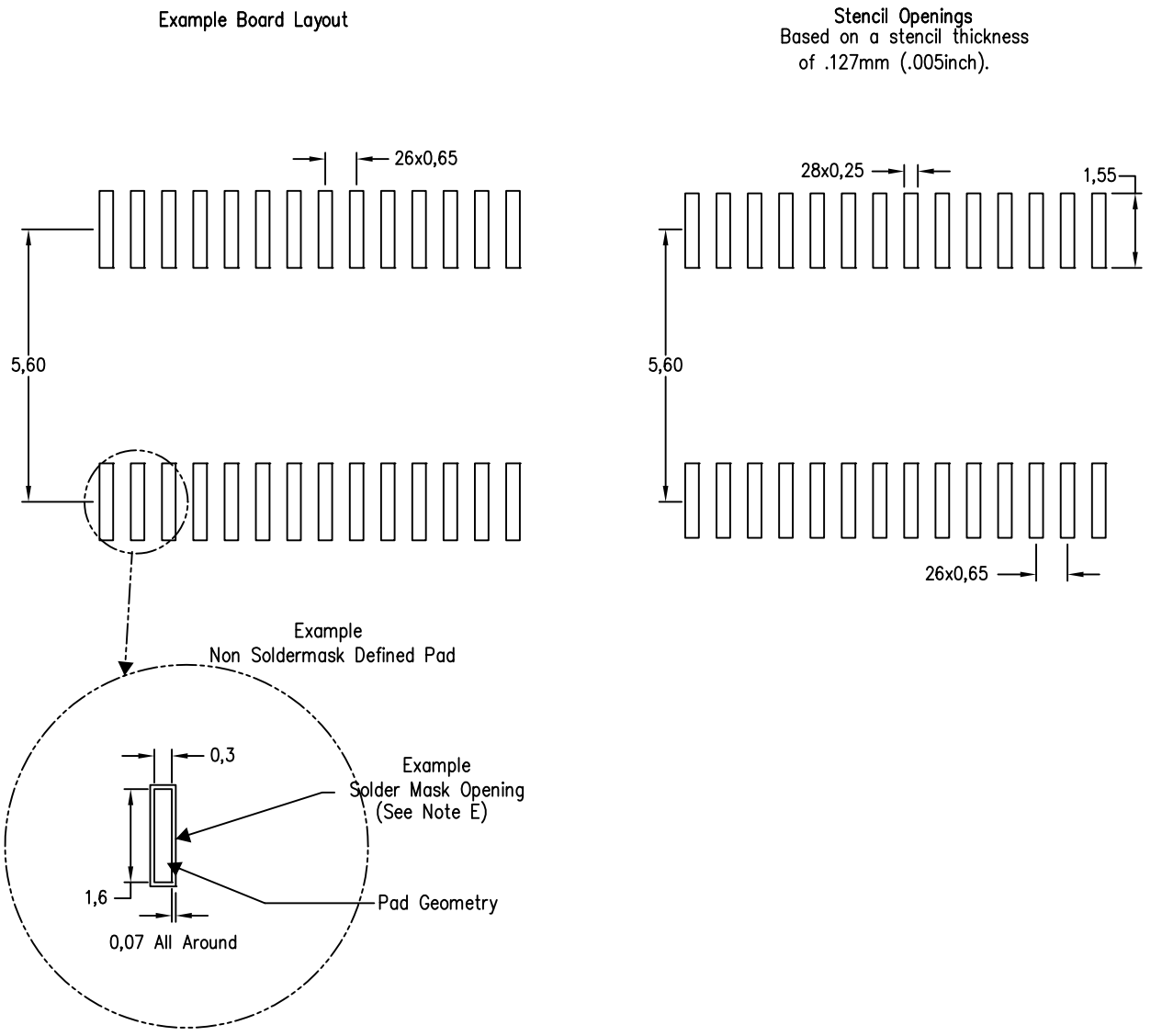
PW (R–PDSO–G28) PLASTIC SMALL OUTLINE



4040064–7/G 02/11

NOTES:
A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M–1994.
B. This drawing is subject to change without notice.
C. Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0,15 each side.
D. Body width does not include interlead flash. Interlead flash shall not exceed 0,25 each side.
E. Falls within JEDEC MO–153

PW (R–PDSO–G28) PLASTIC SMALL OUTLINE



NOTES:
A. All linear dimensions are in millimeters.
B. This drawing is subject to change without notice.
C. Publication IPC–7351 is recommended for alternate design.
D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC–7525 for other stencil recommendations.
E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.

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